- Controlled Baseline
 - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of -40°C to 100°C (A Suffix), and -55°C to 125°C (M Suffix)
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product Change Notification
- Qualification Pedigree[†]
- High-Performance Floating-Point Digital Signal Processor (DSP):
 - SM320VC33-120EP (PGE Suffix)
 - 17-ns Instruction Cycle Time
 - 120 Million Floating-Point Operations Per Second (MFLOPS)
 - 60 Million Instructions Per Second (MIPS)
 - SM320VC33-150EP (GNM Suffix)
 - 13-ns Instruction Cycle Time
 - 150 Million Floating-Point Operations Per Second (MFLOPS)
 - 75 Million Instructions Per Second (MIPS)
- 34K × 32-Bit (1.1M-bit) On-Chip Words of Dual-Access Static Random-Access Memory (SRAM) Configured in 2 × 16K plus 2 × 1K Blocks to improve Internal Performance
- x5 Phase-Locked Loop (PLL) Clock Generator
- Very Low Power: < 200 mW @ 150 MFLOPS
- 32-Bit High-Performance CPU
- 16-/32-Bit Integer and 32-/40-Bit Floating-Point Operations
- Four Internally Decoded Page Strobes to Simplify Interface to I/O and Memory Devices

- Boot-Program Loader
- EDGEMODE Selectable External Interrupts
- 32-Bit Instruction Word, 24-Bit Addresses
- Eight Extended-Precision Registers
- Fabricated Using the 0.18-μm (I_{eff}-Effective Gate Length) Timeline™ Technology by Texas Instruments (TI)
- On-Chip Memory-Mapped Peripherals:
 - One Serial Port
 - Two 32-Bit Timers
 - Direct Memory Access (DMA)
 Coprocessor for Concurrent I/O and CPU
 Operation
- 144-Pin Low-Profile Quad Flatpack (LQFP) (PGE Suffix) and 144-Pin Non-hermetic Ceramic Ball Grid Array (CBGA) (GNM Suffix)
- Two Address Generators With Eight Auxiliary Registers and Two Auxiliary Register Arithmetic Units (ARAUs)
- Two Low-Power Modes
- Two- and Three-Operand Instructions
- Parallel Arithmetic/Logic Unit (ALU) and Multiplier Execution in a Single Cycle
- Block-Repeat Capability
- Zero-Overhead Loops With Single-Cycle Branches
- Conditional Calls and Returns
- Interlocked Instructions for Multiprocessing Support
- Bus-Control Registers Configure Strobe-Control Wait-State Generation
- 1.8-V (Core) and 3.3-V (I/O) Supply Voltages

[†] Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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SM320VC33-EP DIGITAL SIGNAL PROCESSOR

SGUS037C - AUGUST 2002 - REVISED JANUARY 2003

description

The SM320VC33-EP DSP is a 32-bit, floating-point processor manufactured in 0.18-μm four-level-metal CMOS (TImeline) technology. The SM320VC33-EP is part of the SM320C3x[™] generation of DSPs from Texas Instruments.

The SM320C3x internal busing and special digital-signal-processing instruction set have the speed and flexibility to execute up to 150 million floating-point operations per second (MFLOPS). The SM320VC33-EP optimizes speed by implementing functions in hardware that other processors implement through software or microcode. This hardware-intensive approach provides performance previously unavailable on a single chip.

The SM320VC33-EP can perform parallel multiply and ALU operations on integer or floating-point data in a single cycle. Each processor also possesses a general-purpose register file, a program cache, dedicated ARAUs, internal dual-access memories, one DMA channel supporting concurrent I/O, and a short machine-cycle time. High performance and ease of use are the results of these features.

General-purpose applications are greatly enhanced by the large address space, multiprocessor interface, internally and externally generated wait states, one external interface port, two timers, one serial port, and multiple-interrupt structure. The SM320C3x supports a wide variety of system applications from host processor to dedicated coprocessor. High-level-language support is easily implemented through a register-based architecture, large address space, powerful addressing modes, flexible instruction set, and well-supported floating-point arithmetic.

JTAG scan-based emulation logic

The 320VC33 contains a JTAG port for CPU emulation within a chain of any number of other JTAG devices. The JTAG port on this device does not include a pin-by-pin boundary scan for point-to-point board level test. The Boundary Scan tap input and output is internally connected with a single dummy register allowing loop back tests to be performed through that JTAG domain.

The JTAG emulation port of this device also includes two additional pins, EMU0 and EMU1, for global control of multiple processors conforming to the TI emulation standard. These pins are open collector type outputs which are wire ORed and tied high with a pullup. Non-TI emulation devices should not be connected to these pins.

The VC33 instruction register is 8 bits long. Table 1 shows the instruction code. The uses of SAMPLE and HIGHZ opcodes, though defined, have no meaning for the SM320VC33-EP, which has no boundary scan. For example, HIGHZ affects only the dummy cell (no meaning) and does not put the device pins in a high-impedance state.



Table 1. Boundary Scan Instruction Code

INSTRUCTION NAME	INSTRUCTION CODE
EXTEST	0000000
BYPASS	11111111
SAMPLE	0000010
HIGHZ	00000110
PRIVATE1 [†]	00000011
PRIVATE2 [†]	00100000
PRIVATE3 [†]	00100001
PRIVATE4 [†]	00100010
PRIVATE5 [†]	00100011
PRIVATE6 [†]	00100100
PRIVATE7 [†]	00100101
PRIVATE8 [†]	00100110
PRIVATE9 [†]	00100111
PRIVATE10 [†]	00101000
PRIVATE11 [†]	00101001

Boundary is only one dummy cell Boundary is only one dummy cell

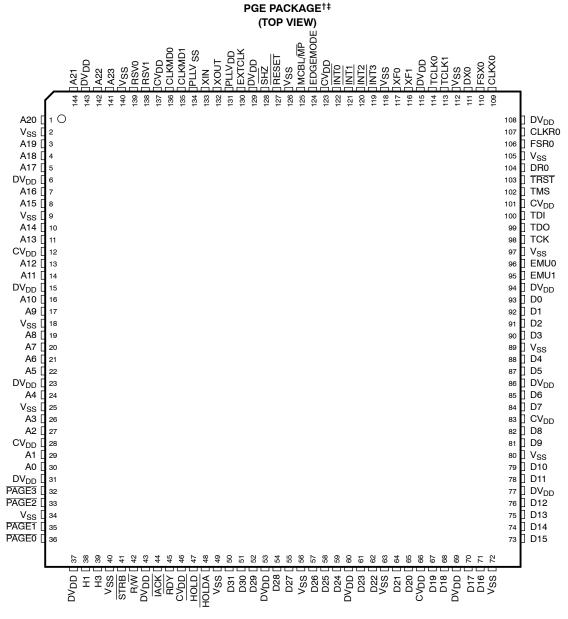
ORDERING INFORMATION

T _C	PACKAGE [‡]	ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 100°C	144-pin low-profile plastic quad flatpack (PGE)	SM320VC33PGEA120EP	SM320VC33PGEA120EP
-55°C to 125°C	144-ball fine pitch Ball Grid Array (GNM)	SM320VC33GNMM150EP	SM320VC33GNMM150EP

[‡] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

[†] Use of Private opcodes could cause the device to operate in an unexpected manner.

pinout



 $^{^{\}dagger}$ DV_{DD} is the power supply for the I/O pins while CV_{DD} is the power supply for the core CPU. V_{SS} is the ground for both the I/O pins and the core CPU.

[‡] PLLV_{DD} and PLLV_{SS} are isolated PLL supply pins that should be externally connected to CV_{DD} and V_{SS}, respectively.

PGE Terminal Assignments[†] (Sorted by Signal Name)

SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER
A0	30	D0	93		31	R/W	42
A1	29	D1	92		37	RDY	45
A2	27	D2	91		43	RESET	127
А3	26	D3	90		53	RSV0	139
A4	24	D4	88		60	RSV1	138
A5	22	D5	87		69	SHZ	128
A6	21	D6	85	DV_DD	77	STRB	41
A7	20	D7	84		86	TCK	98
A8	19	D8	82		94	TCLK0	114
A9	17	D9	81		108	TCLK1	113
A10	16	D10	79		115	TDI	100
A11	14	D11	78		129	TDO	99
A12	13	D12	76		143	TMS	102
A13	11	D13	75	DX0	111	TRST	103
A14	10	D14	74	EDGEMODE	124		2
A15	8	D15	73	EMU0	96		9
A16	7	D16	71	EMU1	95	1	18
A17	5	D17	70	EXTCLK	130	1	25
A18	4	D18	68	FSR0	106	1	34
A19	3	D19	67	FSX0	110	1	40
A20	1	D20	65	H1	38		49
A21	144	D21	64	H3	39	1	56
A22	142	D22	62	HOLD	47] ,	63
A23	141	D23	61	HOLDA	48	V_{SS}	72
CLKMD0	136	D24	59	ĪACK	44		80
CLKMD1	135	D25	58	ĪNT0	122		89
CLKR0	107	D26	57	ĪNT1	121		97
CLKX0	109	D27	55	ĪNT2	120		105
	12	D28	54	ĪNT3	119	1	112
	28	D29	52	MCBL/MP	125		118
	46	D30	51	PAGE0	36		126
0.4	66	D31	50	PAGE1	35		140
CV _{DD}	83	DR0	104	PAGE2	33	XIN	133
	101		6	PAGE3	32	XOUT	132
	123	DV _{DD}	15	PLLV _{DD} ‡	131	XF0	117
	137		23	PLLV _{SS} ‡	134	XF1	116

 $^{^\}dagger$ DV_{DD} is the power supply for the I/O pins while CV_{DD} is the power supply for the core CPU. V_{SS} is the ground for both the I/O pins and the core CPU.

‡ PLLV_{DD} and PLLV_{SS} are isolated PLL supply pins that should be externally connected to CV_{DD} and V_{SS}, respectively.



PGE Terminal Assignments[†] (Sorted by Pin Number)

PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	
1	A20	37	DV_DD	73	D15	109	CLKX0	
2	V _{SS}	38	H1	74	D14	110	FSX0	
3	A19	39	H3	75	D13	111	DX0	
4	A18	40	V_{SS}	76	D12	112	V _{SS}	
5	A17	41	STRB	77	DV_DD	113	TCLK1	
6	DV_DD	42	R/W	78	D11	114	TCLK0	
7	A16	43	DV_DD	79	D10	115	DV _{DD}	
8	A15	44	TACK	80	V _{SS}	116	XF1	
9	V _{SS}	45	RDY	81	D9	117	XF0	
10	A14	46	CV _{DD}	82	D8	118	V _{SS}	
11	A13	47	HOLD	83	CV _{DD}	119	ĪNT3	
12	CV _{DD}	48	HOLDA	84	D7	120	ĪNT2	
13	A12	49	V _{SS}	85	D6	121	ĪNT1	
14	A11	50	D31	86	DV _{DD}	122	ĪNT0	
15	DV_DD	51	D30	87	D5	123	CV _{DD}	
16	A10	52	D29	88	D4	124	EDGEMODE	
17	A9	53	DV_DD	89	V _{SS}	125	MCBL/MP	
18	V _{SS}	54	D28	90	D3	126	V _{SS}	
19	A8	55	D27	91	D2	127	RESET	
20	A7	56	V _{SS}	92	D1	128	SHZ	
21	A6	57	D26	93	D0	129	DV_DD	
22	A5	58	D25	94	DV _{DD}	130	EXTCLK	
23	DV_DD	59	D24	95	EMU1	131	PLLV _{DD} ‡	
24	A4	60	DV_DD	96	EMU0	132	XOUT	
25	V _{SS}	61	D23	97	V _{SS}	133	XIN	
26	A3	62	D22	98	TCK	134	PLLV _{SS} ‡	
27	A2	63	V _{SS}	99	TDO	135	CLKMD1	
28	CV _{DD}	64	D21	100	TDI	136	CLKMD0	
29	A1	65	D20	101	CV _{DD}	137	CV _{DD}	
30	A0	66	CV _{DD}	102	TMS	138	RSV1	
31	DV_DD	67	D19	103	TRST	139	RSV0	
32	PAGE3	68	D18	104	DR0	140	V _{SS}	
33	PAGE2	69	DV_DD	105	V _{SS}	141	A23	
34	V _{SS}	70	D17	106	FSR0	142	A22	
35	PAGE1	71	D16	107	CLKR0	143	DV_DD	
36	PAGE0	72	V _{SS}	108	DV _{DD}	144	A21	

[†] DV_{DD} is the power supply for the I/O pins while CV_{DD} is the power supply for the core CPU. V_{SS} is the ground for both the I/O pins and the core CPU.



 $^{^{\}ddagger}$ PLLV_{DD} and PLLV_{SS} are isolated PLL supply pins that should be externally connected to CV_{DD} and V_{SS}, respectively.

GNM Terminal Assignments[†] (Sorted by Signal Name)

SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER	SIGNAL NAME	PIN NUMBER
A0	J2	D0	G12		M1	R/W	L4
A1	K2	D1	G10	1	N1	RDY	M5
A2	K1	D2	F13]	N4	RESET	В7
А3	J4	D3	G11]	N7	RSV0	B4
A4	H4	D4	H10]	M8	RSV1	D5
A5	H3	D5	H13	1	N12	SHZ	D7
A6	H1	D6	H12	DV_DD	L13	STRB	M4
A7	G4	D7	J10	1	H11	TCK	F10
A8	G1	D8	J11]	F11	TCLK0	C10
A9	G2	D9	J12	1	B12	TCLK1	A11
A10	F3	D10	K13]	A10	TDI	E11
A11	F4	D11	K12	1	A6	TDO	D13
A12	F2	D12	K10	1	A1	TMS	E10
A13	E1	D13	M13	DX0	A12	TRST	C13
A14	E2	D14	L11	EDGEMODE	A7		B1
A15	E4	D15	L12	EMU0	F12		D1
A16	C1	D16	M12	EMU1	E12		G3
A17	C2	D17	L10	EXTCLK	C6		J1
A18	D3	D18	K9	FSR0	C12		L2
A19	C3	D19	N11	FSX	D10		МЗ
A20	B2	D20	M11	H1	L3		M6
A21	D4	D21	M10	H3	N2		L7
A22	A2	D22	K8	HOLD	N5	V	N10
A23	B3	D23	N9	HOLDA	K5	V_{SS}	N13
CLKMD0	C5	D24	M9	ĪACK	K4		K11
CLKMD1	B5	D25	L8	ĪNT0	C8		G13
CLKR0	B13	D26	N8	INT1	В9		E13
CLKX0	B11	D27	M7	INT2	D8		A13
	E3	D28	K7	ĪNT3	A9		C11
	J3	D29	L6	MCBL/MP	B8		C9
	L5	D30	N6	PAGE0	M2		C7
0.4	L9	D31	K6	PAGE1	N3		C4
CV _{DD}	J13	DR0	D11	PAGE2	L1	XF0	B10
	D12		D2	PAGE3	КЗ	XF1	D9
	A8	DV_DD	F1	PLLV _{DD} ‡	A5	XIN	B6
	A3		H2	PLLV _{SS} ‡	A4	XOUT	D6

 $^{^\}dagger$ DV_{DD} is the power supply for the I/O pins while CV_{DD} is the power supply for the core CPU. V_{SS} is the ground for both the I/O pins and the core CPU.

‡ PLLV_{DD} and PLLV_{SS} are isolated PLL supply pins that should be externally connected to CV_{DD} and V_{SS}, respectively.

GNM Terminal Assignments[†] (Sorted by Pin Number)

PIN NUMBER	JMBER NAME NUMBER NAME NUMBER NAME		PIN NUMBER	SIGNAL NAME				
A1	DV _{DD}	C11	V _{SS}	G10			R/W	
A2	A22	C12	FSR0	G11	D3	L5	CV _{DD}	
A3	CV _{DD}	C13	TRST	G12	D0	L6	D29	
A4	PLLV _{SS}	D1	V _{SS}	G13	V _{SS}	L7	V _{SS}	
A5	PLLV _{DD}	D2	DV_DD	H1	A6	L8	D25	
A6	DV_DD	D3	A18	H2	DV_DD	L9	CV _{DD}	
A7	EDGEMODE	D4	A21	НЗ	A5	L10	D17	
A8	CV _{DD}	D5	RSV1	H4	A4	L11	D14	
A9	INT3	D6	XOUT	H10	D4	L12	D15	
A10	DV_DD	D7	SHZ	H11	DV_DD	L13	DV_DD	
A11	TCLK1	D8	ĪNT2	H12	D6	M1	DV_DD	
A12	DX	D9	XF1	H13	D5	M2	PAGE0	
A13	V _{SS}	D10	FSX	J1	V _{SS}	МЗ	V _{SS}	
B1	V _{SS}	D11	DR0	J2	A0	M4	STRB	
B2	A20	D12	CV _{DD}	J3	CV _{DD}	M5	RDY	
B3	A23	D13	TDO	J4	А3	M6	V _{SS}	
B4	RSV0	E1	A13	J10	D7	M7	D27	
B5	CLKMD1	E2	A14	J11	D8	M8	DV_DD	
B6	XIN	E3	CV _{DD}	J12	D9	M9	D24	
B7	RESET	E4	A15	J13	CV _{DD}	M10	D21	
B8	MCBL/MP	E10	TMS	K1	A2	M11	D20	
B9	ĪNT1	E11	TDI	K2	A1	M12	D16	
B10	XF0	E12	EMU1	КЗ	PAGE3	M13	D13	
B11	CLKX0	E13	V _{SS}	K4	ĪACK	N1	DV_DD	
B12	DV_DD	F1	DV_DD	K5	HOLDA	N2	H3	
B13	CLKR	F2	A12	K6	D31	N3	PAGE1	
C1	A16	F3	A10	K7	D28	N4	DV_DD	
C2	A17	F4	A11	K8	D22	N5	HOLD	
C3	A19	F10	TCK	K9	D18	N6	D30	
C4	V _{SS}	F11	DV _{DD}	K10	D12	N7	DV_DD	
C5	CLKMD0	F12	EMU0	K11	V_{SS}	N8	D26	
C6	EXTCLK	F13	D2	K12	D11	N9	D23	
C7	V _{SS}	G1	G1 A8 K13 D10 N10		N10	V _{SS}		
C8	ĪNTO	G2	A9	L1	PAGE2 N11 D19			
C9	V _{SS}	G3	V _{SS}	L2	V _{SS}	N12	DV_DD	
C10	TCLK0	G4	A7	L3	H1	N13	V _{SS}	

 $^{^{\}dagger}$ DV_{DD} is the power supply for the I/O pins while CV_{DD} is the power supply for the core CPU. V_{SS} is the ground for both the I/O pins and the core CPU.



 $^{^{\}ddagger}$ PLLV_{DD} and PLLV_{SS} are isolated PLL supply pins that should be externally connected to CV_{DD} and V_{SS}, respectively.

Terminal Functions

TERMINAL NAME QTY		TVDE†	TYPE† DESCRIPTION			
		I TIPE	DESCRIPTION	WHEN SIGNAL IS Z TYPE‡		
		1	PRIMARY-BUS INTERFACE			
			32-bit data port	S	Н	R
D31-D0	32	I/O/Z	Data port bus keepers. (See Figure 8)	S		
A23-A0	24	O/Z	24-bit address port	S	Н	R
R/W	1	O/Z	Read/write. R/W is high when a read is performed and low when a write is performed over the parallel interface.	S	Н	R
STRB	1	O/Z	Strobe. For all external-accesses	S	Н	
PAGE0 - PAGE3	1	O/Z	Page strobes. Four decoded page strobes for external access	S	Н	R
RDY	1	I	Ready. RDY indicates that the external device is prepared for a transaction completion.			
HOLD	1	I	Hold. When HOLD is a logic low, any ongoing transaction is completed. A23-A0, D31-D0, STRB, and R/W are placed in the high-impedance state and all transactions over the primary-bus interface are held until HOLD becomes a logic high or until the NOHOLD bit of the primary-bus-control register is set.			
HOLDA	1	O/Z	Hold acknowledge. HOLDA is generated in response to a logic-low on HOLD. HOLDA indicates that A23-A0, D31-D0, STRB, and R/W are in the high-impedance state and that all transactions over the bus are held. HOLDA is high in response to a logic-high of HOLD or the NOHOLD bit of the primary-bus-control register is set.	S		
			CONTROL SIGNALS			
RESET	1	ı	Reset. When RESET is a logic low, the device is in the reset condition. When RESET becomes a logic high, execution begins from the location specified by the reset vector.			
EDGEMODE	1	ı	Edge mode. Enables interrupt edge mode detection.			
INT3-INT0	4	I	External interrupts			
IACK	1	O/Z	Internal acknowledge. IACK is generated by the IACK instruction. IACK can be used to indicate when a section of code is being executed.	S		
MCBL/MP	1	I	Microcomputer Bootloader/microprocessor mode-select			
SHZ	1	I	Shutdown high impedance. When active, SHZ places all pins in the high-impedance state. SHZ can be used for board-level testing or to ensure that no dual-drive conditions occur. CAUTION : A low on SHZ corrupts the device memory and register contents. Reset the device with SHZ high to restore it to a known operating condition.			
XF1, XF0	2	I/O/Z	External flags. XF1 and XF0 are used as general-purpose I/Os or to support interlocked processor instruction.			R
			SERIAL PORT 0 SIGNALS			
CLKR0	1	I/O/Z	Serial port 0 receive clock. CLKR0 is the serial shift clock for the serial port 0 receiver.	S		R
CLKX0	1	I/O/Z	Serial port 0 transmit clock. CLKX0 is the serial shift clock for the serial port 0 transmitter.	O S R		
DR0	1	I/O/Z	Data-receive. Serial port 0 receives serial data on DR0.	S		R
DX0	1	I/O/Z	Data-transmit output. Serial port 0 transmits serial data on DX0.	S		R
FSR0	1	I/O/Z	Frame-synchronization pulse for receive. The FSR0 pulse initiates the data-receive process using DR0.	S		R
FSX0	1	I/O/Z	Frame-synchronization pulse for transmit. The FSX0 pulse initiates the data-transmit process using DX0.	S		R

 $[\]S$ Recommended decoupling. Four 0.1 μF for CV $_{DD}$ and eight 0.1 μF for DV $_{DD}$.



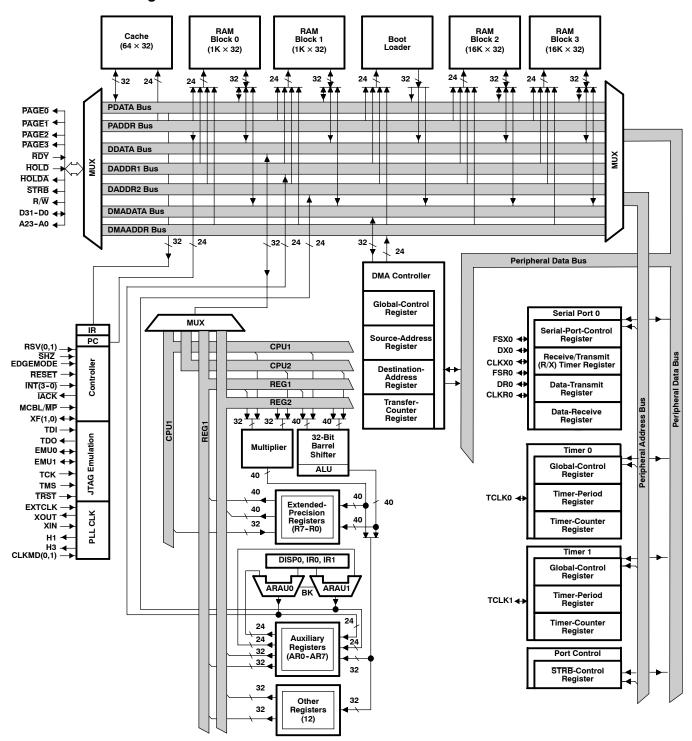
[†] I = input, O = output, Z = high-impedance state † S = \overline{SHZ} active, H = \overline{HOLD} active, R = \overline{RESET} active

Terminal Functions (Continued)

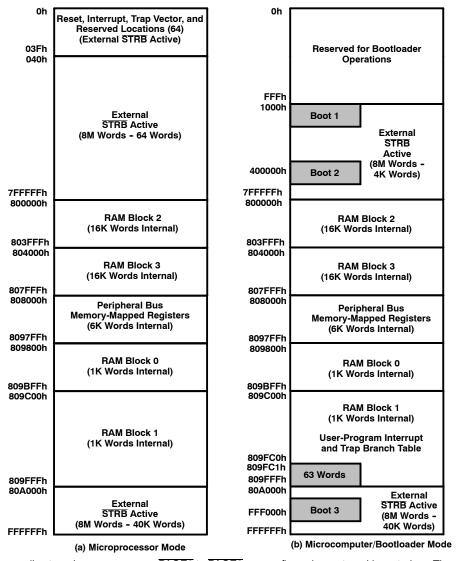
TERMINAL				CONDITIONS						
NAME	QTY	TYPE†	DESCRIPTION	WHEN SIGNAL IS Z TYPE [‡]						
TCLK0	1	I/O/Z	Timer clock 0. As an input, TCLK0 is used by timer 0 to count external pulses. As an output, TCLK0 outputs pulses generated by timer 0.	S R						
TCLK1	1	I/O/Z	Timer clock 1. As an input, TCLK1 is used by timer 1 to count external pulses. As an output, TCLK1 outputs pulses generated by timer 1.	S R						
	SUPPLY AND OSCILLATOR SIGNALS									
H1	1	O/Z	External H1 clock	S						
H3	1	O/Z	External H3 clock	S						
CV _{DD}	8	I	+V $_{DD}.$ Dedicated 1.8-V power supply for the core CPU. All must be connected to a common supply plane. §							
DV _{DD}	16	I	+V $_{DD}.$ Dedicated 3.3-V power supply for the I/O pins. All must be connected to a common supply plane. \S							
V _{SS}	18	I	Ground. All grounds must be connected to a common ground plane.							
PLLV _{DD}	1	I	Internally isolated PLL supply. Connect to CV _{DD} (1.8 V)							
PLLV _{SS}	1	I	Internally isolated PLL ground. Connect to V _{SS}							
EXTCLK	1	I	External clock. Logic level compatible clock input. If the XIN/XOUT oscillator is used, tie this pin to ground.							
XOUT	1	0	Clock out. Output from the internal-crystal oscillator. If a crystal is not used, XOUT should be left unconnected.							
XIN	1	I	Clock in. Internal-oscillator input from a crystal. If EXTCLK is used, tie this pin to ground.							
CLKMD0, CLKMD1	2	I	Clock mode select pins							
RSV0 - RSV1	2	I	Reserved. Use individual pullups to DV _{DD} .							
			JTAG EMULATION							
EMU1-EMU0	2	I/O	Emulation pins 0 and 1, use individual pullups to DV _{DD}							
TDI	1	I	Test data input							
TDO	1	0	Test data output							
TCK	1	I	Test clock							
TMS	1	I	Test mode select							
TRST	1	I	Test reset							

 $^{^{\}dagger}$ I = input, O = output, Z = high-impedance state ‡ S = SHZ active, H = HOLD active, R = RESET active § Recommended decoupling. Four 0.1 μF for CV_{DD} and eight 0.1 μF for DV_{DD}.

functional block diagram



memory map



NOTE A: STRB is active over all external memory ranges. PAGE0 to PAGE3 are configured as external bus strobes. These are simple decoded strobes that have no configuration registers and are active only during external bus activity over the following ranges:

Name	Active range
PAGE0	0000000h - 03FFFFFh
PAGE1	0400000h - 07FFFFh
PAGE2	0800000h - 0BFFFFh
PAGE3	0C00000h – 0FFFFFh
STRB	0000000h - 0FFFFFh

Figure 1. SM320VC33-EP Memory Maps



memory map (continued)

00h	Reset	809FC1h	INTO
01h	INTO	809FC2h	INT1
02h	INT1	809FC3h	INT2
03h	INT2	809FC4h	
04h	INT3		INT3
05h	XINT0	809FC5h	XINT0
06h	RINT0	809FC6h	RINTO
07h		809FC7h	
08h	Reserved	809FC8h	Reserved
09h	TINTO	809FC9h	TINTO
0Ah	TINT1	809FCAh	TINT1
0Bh	DINT	809FCBh	DINT
0Ch		809FCCh	
1Fh	Reserved	809FDFh	Reserved
20h	TRAP 0	809FE0h	TRAP 0
	•		•
	•		
	_		
	•		•
3Bh	TRAP 27	809FFBh	TRAP 27
3Ch		809FFCh	
3Fh	Reserved	809FFFh	Reserved
	(a) Microprocess Mada		(b) Microcomputor/Poetlooder Mede
	(a) Microprocessor Mode	((b) Microcomputer/Bootloader Mode

Figure 2. Reset, Interrupt, and Trap Vector/Branches Memory-Map Locations

memory map (continued)

808000h	DMA Global Control
808004h	DMA Source Address
808006h	DMA Destination Address
808008h	DMA Transfer Counter
808020h	Timer 0 Global Control
808024h	Timer 0 Counter
808028h	Timer 0 Period Register
808030h	Timer 1 Global Control
808034h	Timer 1 Counter
808038h	Timer 1 Period Register
808040h	Serial Global Control
808042h	FSX/DX/CLKX Serial Port Control
808043h	FSR/DR/CLKR Serial Port Control
808044h	Serial R/X Timer Control
808045h	Serial R/X Timer Counter
808046h	Serial R/X Timer Period Register
808048h	Data-Transmit
80804Ch	Data-Receive
808064h	Primary-Bus Control
ļ	

NOTE A: Shading denotes reserved address locations.

Figure 3. Peripheral Bus Memory-Mapped Registers

clock generator

The clock generator provides clocks to the VC33 device, and consists of an internal oscillator and a phase-locked loop (PLL) circuit. The clock generator requires a reference clock input, which can be provided by using a crystal resonator with the internal oscillator, or from an external clock source. The PLL circuit generates the device clock by multiplying the reference clock frequency by a x5 scale factor, allowing use of a clock source with a lower frequency than that of the CPU. The PLL is an adaptive circuit that, once synchronized, locks onto and tracks an input clock signal.

PLL and clock oscillator control

The clock mode control pins are decoded into four operational modes as shown in Figure 4. These modes control clock divide ratios, oscillator, and PLL power (see Table 2).

When an external clock input or crystal is connected, the opposite unused input is simply grounded. An XOR gate then passes one of the two signal sources to the PLL stage. This allows the direct injection of a clock reference into EXTCLK, or 1–20 MHz crystals and ceramic resonators with the oscillator circuit. The two clock sources include:

- A crystal oscillator circuit, where a crystal or ceramic resonator is connected across the XOUT and XIN pins and EXTCLK is grounded.
- An external clock input, where an external clock source is directly connected to the EXTCLK pin, and XOUT
 is left unconnected and XIN is grounded.

When the PLL is initially started, it enters a transitional mode during which the PLL acquires lock with the input signal. Once the PLL is locked, it continues to track and maintain synchronization with the input signal. The PLL is a simple x5 reference multiplier with bypass and power control.

The clock divider, under CPU control, reduces the clock reference by 1 (MAXSPEED), 1/16 (LOWPOWER), or clock stop (IDLE2). Wake-up from the IDLE2 state is accomplished by a RESET or interrupt pin logic-low state.

A divide-by-two SM320C31 equivalent mode of operation is also provided. In this case, the clock output reference is further divided by two with clock synchronization being determined by the timing of RESET falling relative to the present H1/H3 state.

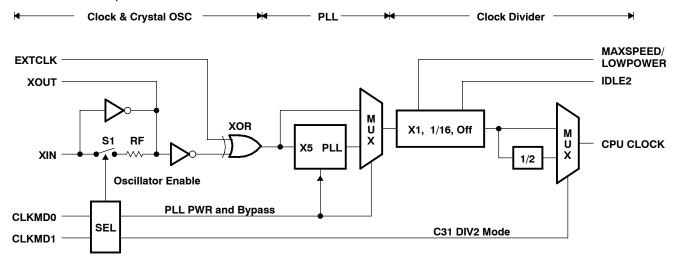


Figure 4. Clock Generation

Table 2. Clock Mode Select Pins

CLKMD0	CLKMD1	FEEDBACK	PLLPWR	RATIO	NOTES
0	0	Off	Off	1	Fully static, very low power
0	1	On	Off	1/2	Oscillator enabled
1	0	On	Off	1	Oscillator enabled
1	1	On	On	5	2 mA @ 60 MHz, 1.8-V PLL power. Oscillator enabled

PLL and clock oscillator control (continued)

Typical crystals in the 8-30 MHz range have a series resistance of 25 Ω , which increases below 8 MHz. To maintain proper filtering and phase relationships, R_d and Z_{out} of the oscillator circuit should be 10x-40x that of the crystal. A series compensation resistor (Rd), shown in Figure 5, is recommended when using lower frequency crystals. The XOUT output, the square wave inverse of XIN, is then filtered by the XOUT output impedance, C1 load capacitor, and R_d (if present). The crystal and C2 input load capacitor then refilters this signal, resulting in a XIN signal that is 75-85% of the oscillator supply voltage.

NOTE: Some ceramic resonators are available in a low-cost, three-terminal package that includes C1 and C2 internally. Typically, ceramic resonators do not provide the frequency accuracy of crystals.

NOTE: Better PLL stability can be achieved using the optional power supply isolation circuit shown in Figure 5. A similar filter can be used to isolate the PLLV_{SS}, as shown in Figure 6. PLLV_{DD} can also be directly connected to CV_{DD}.

FREQUENCY (MHz)	Rd (Ω)	C1 (pF)	C2 (pF)	CL [†] (pF)	RL† (Ω)
2	4.7k	18	18	12	200
5	2.2k	18	18	12	60
10	470	15	15	12	30
15	0	15	12	12	25
20	0	0	0	10	25

Table 3. Typical Crystal Circuit Loading

[†] CL and RL are typical internal series load capacitance and resistance of the crystal.

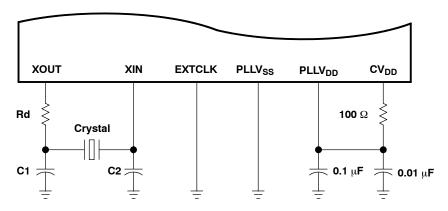


Figure 5. Self-Oscillation Mode

PLL isolation

The internal PLL supplies can be directly connected to CV_{DD} and V_{SS} (0 Ω case) or fully isolated as shown in Figure 6. The RC network prevents the PLL supplies from turning high frequency noise in the CV_{DD} and V_{SS} supplies into jitter.

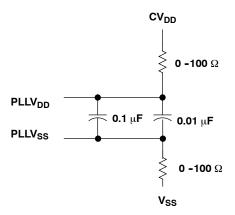


Figure 6. PLL Isolation Circuit Diagram

clock and PLL considerations on initialization

On power up, the CPU clock divide mode can be in MAXSPEED, LOPOWER or IDLE2, or the PLL could be in an undefined mode. RESET falling in the presence of a valid CPU clock is used to clear this state, after which the device will synchronously terminate any external activity.

The 5x Fclkin PLL of the SM320VC33-EP contains an 8-bit PLL-LOCK counter which will cause the PLL to output a frequency of Fclkin/2 during the initial ramp. This counter, however, does not increment while RESET is low or in the absence of an input clock. A minimum of 256 input clocks are required before the first falling edge of reset for the PLL to output to clear this counter. The setup and behavior that is seen is as follows.

Power is applied to the DSP with RESET low and the input clock high or low. A clock is applied (RESET is still low) and the PLL appears to lock on to the input clock, producing the expected x5 output frequency. RESET is driven high and the PLL output immediately drops to Fclkin/2 for up to 256 input cycles or 128 of the Fclkin/2 output cycles. The PLL/CPU clock then switches to x5 mode.

The switch over is synchronous and does not create a clock glitch, so the only effect is that the CPU will run slow for up to the first 128 cycles after reset goes high. Once the PLL has stabilized, the counter will remain cleared and subsequent resets will not exhibit this condition.

power sequencing considerations

Though an internal ESD and CMOS latchup protection diode exists between CV_{DD} and DV_{DD} , it should not be considered a current-carrying device on power up. An external Schottky diode should be used to prevent CV_{DD} from exceeding DV_{DD} by more than 0.7 V. The effect of this diode during power up is that if CV_{DD} is powered up first, DV_{DD} will follow by one diode drop even when the DV_{DD} supply is not active.

Typical systems using LDOs of the same family type for both DV_{DD} and CV_{DD} will track each other during power up. In most cases, this is acceptable; but if a high-impedance pin state is required on power up, the \overline{SHZ} pin can be used to asynchronously disable all outputs. \overline{RESET} should not be used in this case since some signals require an active clock for \overline{RESET} to have an effect and the clock may not yet be active. The internal core logic becomes functional at approximately 0.8 V while the external pin IO becomes active at about 1.5 V.



EDGEMODE

When EDGEMODE = 1, a sampled digital delay line is decoded to generate a pulse on the falling edge of the interrupt pin. To ensure interrupt recognition, input signal logic-high and logic-low states must be held longer than the synchronizer delay of one CPU clock cycle. Holding these inputs to no less than two cycles in both the logic-low and logic-high states is sufficient.

When EDGEMODE = 0, a logic-low interrupt pin will continually set the corresponding interrupt flag. The CPU or DMA can clear this flag within two cycles of it being set. This is the maximum interrupt width that can be applied if only one interrupt is to be recognized. The CPU can manually clear IF bits within an interrupt service routine (ISR), effectively lengthening the maximum ISR width.

After reset, EDGEMODE is temporarily disabled, allowing logic-low INT pins to be detected for bootload operation.

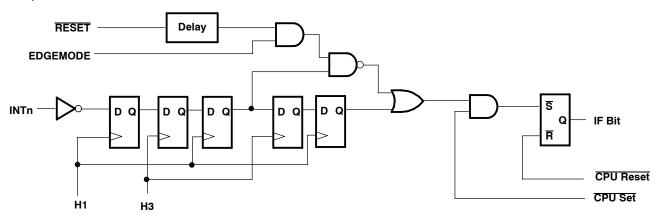


Figure 7. EDGEMODE and Interrupt Flag Circuit

reset operation

When RESET is applied, the CPU attempts to safely exit any pending read or write operations that may be in progress. This can take as many as 10 CPU cycles, after which, the address, data, and control pins will be in an inactive or high-impedance state.

When both RESET and SHZ are applied, the device immediately enters the reset state with the pins held in high-impedance mode. SHZ should then be disabled at least 10 CPU cycles before RESET is set high. SHZ can be used during power-up sequencing to prevent undefined address, data, and control pins, avoiding system conflicts.

PAGE0 - PAGE3 select lines

To facilitate simpler and higher speed connection to external devices, the SM320VC33-EP includes four predecoded select pins that have the same timings as STRB. These pins are decoded from A22, A23, and STRB and are active only during external accesses over the ranges shown in Table 4. All external bus accesses are controlled by a single bus control register.

Table 4.	PAGE0	- PAGE3	Ranges
----------	-------	---------	--------

	START	END
PAGE0	0x000000	0x3FFFFF
PAGE1	0x400000	0x7FFFFF
PAGE2	0x800000	0xBFFFFF
PAGE3	0xC00000	0xFFFFF



data bus I/O buffer

The circuit shown in Figure 8 is incorporated into each data pin to lightly "hold" the last driven value on the data bus pins when the DSP or an external device is not actively driving the bus. Each bus keeper is built from a three-state driver with nominal 15 k Ω output resistance which is fed back to the input in a positive feedback configuration. The resistance isolated driver then pulls the output in one direction or the other keeping the last driven value. This circuit is enabled in all functional modes and is only disabled when $\overline{\text{SHZ}}$ is pulled low.

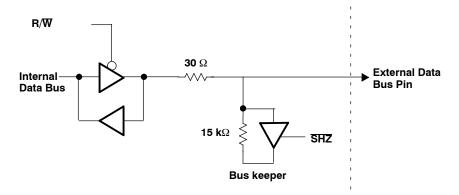


Figure 8. Bus Keeper Circuit

For an external device to change the state of these pins, it must be able to drive a small dc current until the driver threshold is crossed. At the crossover point, the driver changes state, agreeing with the external driver and assisting the change. The voltage threshold of the bus keeper is approximately at 50% of the DV_{DD} supply voltage. The typical output impedance of 30 Ω for all SM320VC33-EP I/O pins is easily capable of meeting this requirement.

using external logic with the READY pin

The key to designing external wait-state logic is the internal bus control register and associated internal logic that logically combines the external READY pin with the much faster on-chip bus control logic. This essentially allows slow external logic to interact with the bus while easily meeting the READY input timings. It is also relevant to mention that the combined ready signals are sampled on the rising edge of the internal H1 clock. Please refer to Figure 9 for the following examples.

example 1

A simple 0 or WTCNT wait-state decoder can be created by simply tying an address line back to the READY pin and selecting the AND option. When the tied back address is low, the bus runs with 0 wait states. When the tied back address is high, the bus is controlled by the internal wait-state counter.

By enabling the bank compare logic, proper operation is further ensured by inserting a null cycle before a read on the next bank is performed (writes are not pre-extended). This extra time can also be used by external logic to affect the feedback path.

example 2

An N-WTCNT minimum wait-state decoder can also be created by tying back an address line to READY and logically ORing it with the internal bank compare and wait count signals. When the address pin is low, bus timing is determined by the internal WTCNT and BNKCMP settings. When the address line is high, the bus can run no faster than the WTCNT counter and is extended as long as READY is held high.



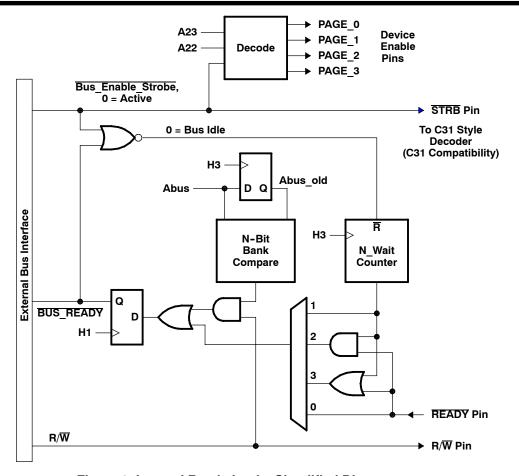


Figure 9. Internal Ready Logic, Simplified Diagram

example 2 (continued)

Table 5. MUX Select (Bus Control Register Bits 4 and 3)

BIT 4	BIT 3	RESULTS
0	0	Ignore internal wait counter and use only external READY
0	1	Use only internal wait counter and ignore ready pin
1	0	Logically AND internal wait counter with ready pin
1	1	Logically OR internal wait counter with ready pin (reset default)

posted writes

External writes are effectively "posted" to the bus, which then acts like an output latch until the write completes. Therefore, if the application code is executing internally, it can perform a very slow external write with no penalty since the bus acts like it has a one-level-deep write FIFO.

data bus I/O buffer

The circuit shown in Figure 10 is incorporated into each data pin to lightly "hold" the last driven value on the data bus pins when the DSP or an external device is not actively driving the bus. Each bus keeper is built from a three-state driver with nominal 15 k Ω output resistance which is fed back to the input in a positive feedback configuration. The resistance isolated driver then pulls the output in one direction or the other keeping the last driven value. This circuit is enabled in all functional modes and is only disabled when $\overline{\text{SHZ}}$ is pulled low.

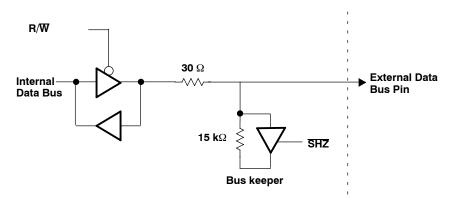


Figure 10. Bus Keeper Circuit

For an external device to change the state of these pins, it must be able to drive a small dc current until the driver threshold is crossed. At the crossover point, the driver changes state, agreeing with the external driver and assisting the change. The voltage threshold of the bus keeper is approximately at 50% of the DV_{DD} supply voltage. The typical output impedance of 30 Ω for all SM320VC33-EP I/O pins is easily capable of meeting this requirement.

bootloader operation

When MCBL/MP = 1, an internal ROM is decoded into the address range of 0x000000-0x000FFF. Therefore, when reset occurs, execution begins within the internal ROM program and vector space. No external activity will be evident until one of the boot options is enabled. These options are enabled by pulling an external interrupt pin low, which the boot-load software then detects, causing a particular routine to be executed (see Table 6).

ACTIVE INTERRUPT	ADDRESS/SOURCE WHERE BOOT DATA IS READ FROM	DATA FORMAT
INTO	0x001000	8, 16, or 32-bit width
ĪNT1	0x400000	8, 16, or 32-bit width
ĪNT2	0xFFF000	8, 16, or 32-bit width
ĪNT3	Serial Port	32-bit, external clock, and frame synch

Table 6. INTO - INT3 Sources

When MCBL/MP = 1, the reset and interrupt vectors are hard-coded within the internal ROM. Since this is a read-only device, these vectors cannot be modified. To enable user-defined interrupt routines, the internal vectors contain fixed values that point to an internal section of SRAM beginning at 0x809FC1. Code execution begins at these locations so it is important to place branch instructions (to the interrupt routine) at these locations and not vectors.

The bootloader program requires a small stack space for calls and returns. Two SRAM locations at 0x809800 and 0x809801 are used for this stack. Data should not be boot loaded into these locations as this will corrupt the bootloader program run-time stack. After the boot-load operation is complete, a program can reclaim these locations. The simplest solution is to begin a program stack or uninitialized data section at 0x809800.

For additional detail on bootloader operation including the bootloader source code, see the *TMS320C3x User's Guide* (literature number SPRU031).

A bit I/O line or external logic can be used to safely disable the MCBL mode after bootloading is complete. However, to ensure proper operation, the CPU should not be currently executing code or using external data as the change takes place. In the following example, the XF0 pin is 3-state on reset, which allows the pullup resistor to place the DSP in MCBL mode. The following code, placed at the beginning of an application then causes the XF0 pin to become an active-logic-low output, changing the DSP mode to MP. The cache-enable and RPTS instructions are used since they cause the LDI instruction to be executed multiple times even though it has been fetched only once (before the mode change). In other words, the RPTS instruction acts as a one-level-deep program cache for externally executed code. If the application code is to be executed from internal RAM, no special provisions are needed.

```
LDI 8000h,ST; Enable the cache

RPTS 4; RPTS will fetch the following opcode 1 time

LDI 2h, IOF; Drive MCBL/MP=0 for several cycles allowing; the pipeline to clear

RESET

DVDD

SM320VC33-EP

XFO
MCBL/MP
```

Figure 11. Changing Bootload Select Pin



JTAG emulation

Though the SM320VC33-EP contains a JTAG debug port which allows multiple JTAG-enabled chips to be daisy-chained, boundary scan of the pins is not supported. If the pin scan path is selected, it is routed through a null register with a length of one. For additional information concerning the emulation interface, see JTAG/MPSD Emulation Technical Reference (literature number SPDU079).

designing a target system emulator connector (14-pin header)

JTAG target devices support emulation through a dedicated emulation port. This port is a superset of the test access port standard and is accessed by the emulator. To communicate with the emulator, the **target system must have a 14-pin header** (two rows of seven pins) with the connections that are shown in Figure 12. Table 7 describes the emulation signals.

TMS	1	2	TRST
TDI	3	4	GND
PD (V _{CC})	5	6	no pin (key)†
TDO	7	8	GND
TCK_RET	9	10	GND
TCK	11	12	GND
EMU0	13	14	EMU1

Header Dimensions:

Pin-to-pin spacing, 0.100 in. (X,Y) Pin width, 0.025-in. square post Pin length, 0.235-in. nominal

Figure 12. 14-Pin Header Signals and Header Dimensions

Table 7. 14-Pin Header Signal Descriptions

SIGNAL	DESCRIPTION	EMULATOR [†] STATE	TARGET [†] STATE
TMS [‡]	Test mode select	0	1
TDI	Test data input	0	I
TDO	Test data output	I	0
тск	Test clock. TCK is a 10.368-MHz clock source from the emulation cable pod. This signal can be used to drive the system test clock	0	I
TRST§	Test reset	0	1
EMU0 ^{‡¶}	Emulation pin 0	I	I/O
EMU1 ^{‡¶}	Emulation pin 1	1	I/O
PD(V _{CC})	Presence detect. Indicates that the emulation cable is connected and that the target is powered up. PD should be tied to $V_{\rm CC}$ in the target system.	1	0
TCK_RET	Test clock return. Test clock input to the emulator. May be a buffered or unbuffered version of TCK.	1	0
GND	Ground		

[†] I = input; O = output

[¶] EMU0 and EMU1 are I/O drivers configured as open-drain (open-collector) drivers. They are used as bidirectional signals for emulation global start and stop.



[†] While the corresponding female position on the cable connector is plugged to prevent improper connection, the cable lead for pin 6 is present in the cable and is grounded, as shown in the schematics and wiring diagrams in this document.

[‡] Use 1-50K pullups for TMS, EMU0 and EMU1.

[§] Use 1–50K pulldown for TRST. Do not use pullup resistors on TRST: it has an internal pulldown device. In a low-noise environment, TRST can be left floating. In a high-noise environment, an additional pulldown resistor may be needed. (The size of this resistor should be based on electrical current considerations.)

designing a target system emulator connector (14-pin header) (continued)

Although other headers can be used, recommended parts include:

straight header, unshroudedDuPont Connector Systems part numbers: 65610-114

65611-114

00011 11

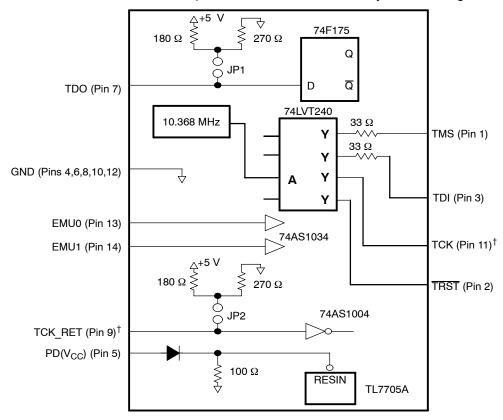
67996-114

67997-114

JTAG emulator cable pod logic

Figure 13 shows a portion of the emulator cable pod. The functional features of the pod are as follows:

- Signals TDO and TCK_RET can be parallel-terminated inside the pod if required by the application. By default, these signals are not terminated.
- Signal TCK is driven with a 74LVT240 device. Because of the high-current drive (32 mA I_{OL}/I_{OH}), this signal
 can be parallel-terminated. If TCK is tied to TCK_RET, the parallel terminator in the pod can be used.
- Signals TMS and TDI can be generated from the falling edge of TCK_RET, according to the bus slave device timing rules.
- Signals TMS and TDI are series-terminated to reduce signal reflections.
- A 10.368-MHz test clock source is provided. Other test clocks may be used for greater flexibility.



[†] The emulator pod uses TCK_RET as its clock source for internal synchronization. TCK is provided as an optional target system test clock source.

Figure 13. JTAG Emulator Cable Pod Interface



device and development support tool nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all TMS320™ DSP family devices and support tools. Each TMS320™ DSP member has one of three prefixes: TMX, TMP, or TMS, and each SMJ320™ DSP member has one of three prefixes: SMX, SM, or SMJ. Texas Instruments recommends two of three possible prefix designators for its support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (TMX/TMDX) through fully qualified production devices/tools (TMS/TMDS). This development flow is defined below.

Device development evolutionary flow:

SMX Experimental device that is not necessarily representative of the final device's electrical

specifications

TMP Final silicon die that conforms to the device's electrical specifications but has not completed

quality and reliability verification

SM/SMJ Fully-qualified production device

Support tool development evolutionary flow:

TMDX Development support product that has not yet completed Texas Instruments internal qualification

testing.

TMDS Fully qualified development support product

TMX and TMP devices and TMDX development support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

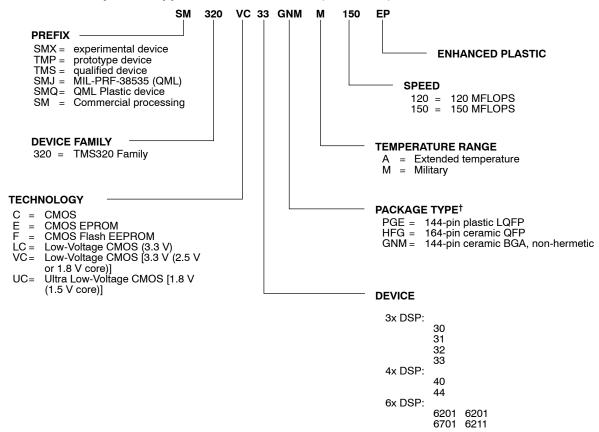
TMS devices and TMDS development support tools have been characterized fully, and the quality and reliability of the device has been demonstrated fully. Tl's standard warranty applies.

Predictions show that prototype devices (TMX or TMP) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (for example, GNM) and temperature range (for example, M). Figure 14 provides a legend for reading the complete device name for any TMS320™ DSP family member.

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device and development support tool nomenclature (continued)



NOTE: Not all speed, package, process, and temperature combinations are available.

† QFP = Quad Flat Package LQFP = Low-Profile Quad Flat Package BGA = Ball Grid Array

Figure 14. TMS320™ DSP Device Nomenclature

absolute maximum ratings over specified temperature range (unless otherwise noted)†

Supply voltage range, DV _{DD} [‡]	0.3 V to 4 V
Supply voltage range, CV _{DD} [‡]	0.3 V to 2.4 V
Input voltage range, V _I §	1 V to 4.6 V
Output voltage range, VO	0.3 V to 4.6 V
Continuous power dissipation (worst case) [¶]	500 mW
Operating case temperature range, T _C (PGE package)	40°C to 100°C
T _C (GNM package)	55°C to 125°C
Storage temperature range, T _{stg} #	55°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions^{‡||*}

			MIN	NOM	MAX	UNIT
CV_{DD}	Supply voltage for the core CPU□		1.71	1.8	1.89	V
DV_DD	D Supply voltage for the I/O pins [◊]		3	3.3	3.6	V
V_{SS}	SS Supply ground			0		V
V_{IH}	High-level input voltage		0.7 x DV _{DD}		DV _{DD} + 0.3§	V
V_{IL}	Low-level input voltage		-0.3§		0.3 x DV _{DD}	V
I _{OH}	High-level output current				4	mA
I_{OL}	Low-level output current				4	mA
_	o .:	A suffix	-40		100	
T _C Operating case temperature		M suffix	-55		125	°C
C_L	Capacitive load per output pin	•			30	pF

[‡] All voltage values are with respect to V_{SS}.



[‡] All voltage values are with respect to V_{SS}.

[§] Absolute dc input level should not exceed the DV_{DD} or V_{SS} supply rails by more than 0.3 V. An instantaneous low current pulse of < 2 ns, < 10 mA, and < 1 V amplitude is permissable.

Actual operating power is much lower. This value was obtained under specially produced worst-case test conditions for the SM320VC33-EP, which are not sustained during normal device operation. These conditions consist of continuous parallel writes of a checkerboard pattern to the external data and address buses at the maximum possible rate with a capacitive load of 30 pF. See normal (I_{CC}) current specification in the electrical characteristics table and also read *TMS320C3x General-Purpose Applications* (literature number SPRU194).

[#] Long term high-temperature storage and/or extended use at maximum recommended operating conditions may result in a reduction of overall device life. See www.ti.com/ep_quality for additional information on enhanced plastic packaging.

[§] Absolute dc input level should not exceed the DV_{DD} or V_{SS} supply rails by more than 0.3 V. An instantaneous low current pulse of < 2 ns, < 10 mA, and < 1 V amplitude is permissable.

All inputs and I/O pins are configured as inputs.

[★]All input and I/O pins use a Schmidt hysteresis inputs except SHZ and D0-D31. Hysteresis is approximately 10% of DV_{DD} and is centered at 0.5 x DV_{DD}.

[□]CV_{DD} should not exceed DV_{DD} by more than 0.7 V. (Use a Schottky clamp diode between these supplies.)

 $[\]lozenge$ DV_DD should not exceed CV_DD by more than 2.5 V.

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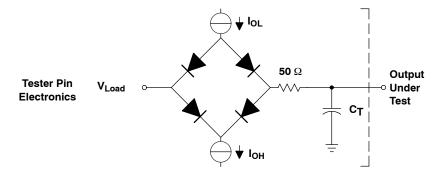
electrical characteristics over recommended ranges of supply voltage (unless otherwise noted)[†]

	PARAMETER	TEST CO	NDITIONS‡	MIN	TYP§	MAX	UNIT
V_{OH}	High-level output voltage	$DV_{DD} = MIN$, $I_{OH} = MAX$		2.4			V
V_{OL}	Low-level output voltage	$DV_{DD} = MIN, I_{OL} = MA$	λX			0.4	V
IZ	High-impedance current	$T_C = 25^{\circ}C$, $DV_{DD} = MA$	X	-5		+5	μΑ
lı	Input current	$T_C = 25^{\circ}C$, $V_I = V_{SS}$ to	DV _{DD}	-5		+5	μΑ
I _{IPU}	Input current (with internal pullup)	Inputs with internal pullup	s [¶]	-600		10	μΑ
I _{IPD}	Input current (with internal pulldown)	Inputs with internal pulldo	wns [¶]	600		-10	μΑ
I _{BKU}	Input current (with bus keeper) pullup#	Bus keeper opposes until conditions match		-600		10	μΑ
I _{BKD}	Input current (with bus keeper) pulldown#			600		-10	μΑ
	Supply current, pins [∥] ☆	T _C = 25°C, DV _{DD} = MAX	f _x = 60 MHz, VC33-120		20	120	
I _{DDD}			f _x = 75 MHz, VC33-150		25	260	mA
	o i opili.	T _C = 25°C,	f _x = 60 MHz, VC33-120		50	80	
IDDC	Supply current, core CPUll∻	CV _{DD} = MAX	f _x = 75 MHz, VC33-150		60	215	mA
		PLL enabled, oscillator er	nabled		2		mA
I_{DD}	IDLE2, Supply current, IDDD plus IDDC	PLL disabled, oscillator enabled			500		•
		PLL disabled, oscillator disabled, FCLK = 0			50		μΑ
	The transfer of	All inputs except XIN XIN				10*	
Ci	Input capacitance					10*	pF
Co	Output capacitance					10*	pF

^{*} Not production tested

☆f_x is the PLL output clock frequency.

PARAMETER MEASUREMENT INFORMATION



Where: I_{OI} = 4 mA (all outputs) for dc levels test.

 I_{O} and I_{OH} are adjusted during ac timing analysis to achieve an ac termination of 50 Ω

 $V_{LOAD} = DV_{DD}/2$

 C_T = 40-pF typical load-circuit capacitance

Figure 15. Test Load Circuit



[†] All voltage values are with respect to V_{SS}.

For test conditions shown as MIN, MAX, or NOM, use the appropriate value specified in the recommended operating conditions table.

 $[\]S$ For VC33, all typical values are at DV_{DD} = 3.3, CV_{DD} = 1.8 V, T_C (case temperature) = 25°C.

Pins with internal pullup devices: TDI, TCK, and TMS. Pin with internal pulldown device: TRST.

[#] Pins D0-D31 include internal bus keepers that maintain valid logic levels when the bus is not driven (see Figure 8).

Actual operating current is less than this maximum value. This value was obtained under specially produced worst-case test conditions, which are not sustained during normal device operation. These conditions consist of continuous parallel writes of a checkerboard pattern at the maximum rate possible. See *TMS320C3x General-Purpose Applications* (literature number SPRU194).

PARAMETER MEASUREMENT INFORMATION

timing parameter symbology

Timing parameter symbols used herein were created in accordance with JEDEC Standard 100. In order to shorten the symbols, some of the pin names and other related terminology have been abbreviated as follows, unless otherwise noted:

Lowercase su	bscripts and their meanings	Letters and sy	Letters and symbols and their meanings			
а	access time	Н	High			
С	cycle time (period)	L	Low			
d	delay time	V	Valid			
dis	disable time	Z	High Impedance			
en	enable time					
f	fall time					
h	hold time					
r	rise time					
su	setup time					
t	transition time					
V	valid time					
w	pulse duration (width)					
x	unknown, changing, or don't care level					

Additional symbols and their meaning

•	S .		
Α	Address lines (A23-A0)	Н	H1 and H3
ASYNCH	Asynchronous reset signals (XF0, XF1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, TCLK0, and TCLK1)	HOLD	HOLD
CLKX	CLKX0	HOLDA	HOLDA
CLKR	CLKR0	IACK	IACK
CONTROL	Control signals	INT	INT3-INT0
D	Data lines (D31-D0)	PAGE	PAGE0-PAGE3
DR	DR	RDY	RDY
DX	DX	RW	R/W
EXTCLK	EXTCLK	RW	R/\overline{W}
FS	FSX/R	RESET	RESET
FSX	FSX0	S	STRB
FSR	FSR0	SCK	CLKX/R
GPI	General-purpose input	SHZ	SHZ
GPIO	General-purpose input/output; peripheral pin (CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, TCLK0, and TCLK1)	TCLK	TCLK0, TCLK1, or TCLKx
GPO	General-purpose output	XF	XF0, XF1, or XFx
H1	H1	XF0	XF0
H3	H3	XF1	XF1
		XIN	XIN

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phase-locked loop (PLL) circuit timing

phase-locked loop characteristics using EXTCLK or on-chip crystal oscillator[†]

	PARAMETER	MIN	MAX	UNIT
F _{pllin}	Frequency range, PLL input	5*	15*	MHz
F _{pllout}	Frequency range, PLL output	25*	75*	MHz
I _{pll}	PLL current, CV _{DD} supply		2*	mA
P _{pll}	PLL power, CV _{DD} supply		5*	mW
PLL _{dc}	PLL output duty cycle at H1	45*	55*	%
PLLJ	PLL output jitter, F _{pllout} = 25 MHz		400*	ps
PLL _{LOCK}	PLL lock time in input cycles		1000	cycles

^{*} Not production tested

To ensure clean internal clock references, the minimal low and high pulse durations must be maintained. At high frequencies, this may require a fast rise and fall time as well as a tightly controlled duty cycle. At lower frequencies, these requirements are less restrictive when in x1 and x0.5 modes. The PLL, however, must have an input duty cycle of between 40% and 60% for proper operation.

 $^{^\}dagger$ Duty cycle is defined as 100*t1/(t1+t2)%

clock circuit timing

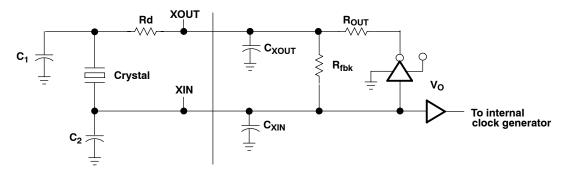
The following table defines the timing parameters for the clock circuit signals.

circuit parameters for on-chip crystal oscillator[†] (see Figure 16)

	PARAMETER	MIN	TYP	MAX	UNIT
Vo	Oscillator internal supply voltage		CV _{DD}		V
Fo	Fundamental mode frequency range	1*		20*	MHz
V_{bias}	DC bias point (input threshold)	40*	50	60*	%V _O
R _{fbk}	Feedback resistance	100*	300	500*	kΩ
R _{out}	Small signal ac output impedance	250*	500	1000*	Ω
V _{xoutac}	The ac output voltage with test crystal [‡]		85		%V _O
V _{xinac}	The ac input voltage with test crystal‡		85		%V _O
V_{xoutl}	$V_{xin} = V_{xinh}$, $I_{xout} = 0$, $F_O=0$ (logic input)	V _{SS} - 0.1*		V _{SS} + 0.3*	V
V_{xouth}	$V_{xin} = V_{xinl}$, $I_{xout} = 0$, $F_{O}=0$ (logic input)	CV _{DD} - 0.3*		CV _{DD} + 0.1*	V
V _{inl}	When used for logic level input, oscillator enabled	-0.3*		0.2 x V _O *	V
V _{inh}	When used for logic level input, oscillator enabled	0.8 x V _O *		DV _{DD} + 0.3*	V
V_{xinh}	When used for logic level input, oscillator disabled	0.7 x DV _{DD}		DV _{DD} + 0.3	V
C _{xout}	XOUT internal load capacitance	2*	3	5*	pF
C _{xin}	XIN internal load capacitance	2*	3	5*	pF
t _{d(XIN-H1)}	Delay time, XIN to H1 x1 and x0.5 modes	2	5.5	8	ns
I _{inl}	Input current, feedback enabled, V _{il} = 0			50*	μΑ
I _{inh}	Input current, feedback enabled, V _{il} = V _{ih}			-50*	μΑ

^{*} Not production tested

[‡] Signal amplitude is dependent on the crystal and load used.



NOTE A: See Table 3 for value of Rd.

Figure 16. On-Chip Oscillator Circuit

[†] This circuit is intended for series resonant fundamental mode operation.

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clock circuit timing (continued)

The following tables define the timing requirements and switching characteristics for EXTCLK.

timing requirements for EXTCLK, all modes (see Figure 17 and Figure 18)

			MIN	MAX	UNIT
t _{r(EXTCLK)}	Rise time, EXTCLK	F = F _{max} , x0.5 and x1 modes		1*	
		F < F _{max}		4*	ns
t _{f(EXTCLK)}	Fall time, EXTCLK	F = F _{max} , x0.5 and x1 modes		1*	
		F < F _{max}		4*	ns
		x5 mode	21*		
t _{w(EXTCLKL)}	Pulse duration, EXTCLK low	x1 mode	5.5*		ns
,		x0.5 mode	4.0*		
t _{w(EXTCLKH)}		x5 mode	21*		
	Pulse duration, EXTCLK high	x1 mode	5.5*		ns
,		x0.5 mode	4.0*		
	Duty cycle, EXTCLK [t _{w(EXTCLKH)} / t _{c(H)]}	x5 PLL mode	40*	60*	
t _{dc(EXTCLK)}		x1 and x0.5 modes, F = max	45	55	%
, ,	, , , ,	x1 and x0.5 modes, F = 0 Hz	0*	100*	
		x5 mode	66.7*	200*	
t _{c(EXTCLK)}	Cycle time, EXTCLK	x1 mode	13.3		ns
		x0.5 mode	10*		
F _{ext}		x5 mode	5*	15*	
	Frequency range, 1/t _{c(EXTCLK)}	x1 mode	0	75	MHz
	, ,	x0.5 mode	0*	100*	

^{*} Not production tested

switching characteristics for EXTCLK over recommended operating conditions, all modes (see Figure 17 and Figure 18)

	PARAMETER		MIN	TYP	MAX	UNIT
V_{mid}	Mid-level, used to measure duty cycle		0.5 x DV _{DD}			V
t _{d(EXTCLK-H)}	Delay time, EXTCLK to H1 and H3	x1 mode	2*	4.5	7*	ns
		x0.5 mode	2*	4.5	7*	
t _{r(H)}	Rise time, H1 and H3				3*	ns
t _{f(H)}	Fall time, H1 and H3				3*	ns
t _{d(HL-HH)}	Delay time, from H1 low to H3 high or from H3 low to H1 high		-1.5*		2*	ns
t _{c(H)}		x5 PLL mode		1/(5 x fext)		
	Cycle time, H1 and H3	x1 mode	1/fext			ns
	x0.5 mode			2/fext		

^{*} Not production tested



clock circuit timing (continued)

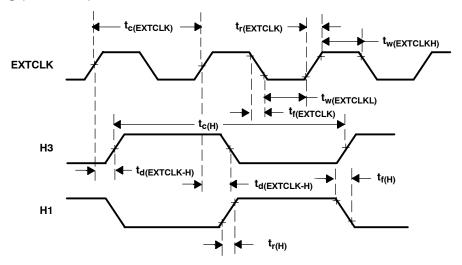
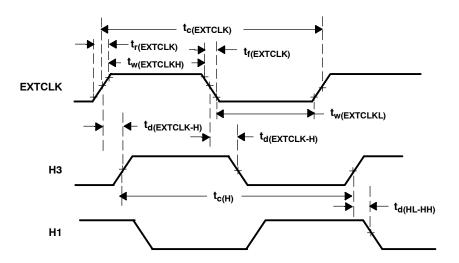


Figure 17. Divide-By-Two Mode



NOTE A: EXTCLK is held low.

Figure 18. Divide-By-One Mode

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memory read/write timing

The following tables define memory read/write timing parameters for STRB.

timing requirements for memory read/write[†] (see Figure 19, Figure 20, and Figure 21)

			VC33-120		VC33-150		
			MIN	MAX	MIN	MAX	UNIT
t _{su(D-H1L)} R	Setup time, Data before H1 low (read)		5*		5*		ns
t _{h(H1L-D)R}	Hold time, Data after H1 low (read)		-1*		-1*		ns
t _{su(RDY-H1H)}	Setup time, RDY before H1 high		5		5		ns
t _{h(H1H-RDY)}	Hold time, RDY after H1 high		-1*		-1*		ns
t _{d(A-RDY)}	Delay time, Address valid to RDY			P - 7*‡		P - 6*‡	ns
t _{v(A-D)}	Valid time, Data valid after address PAGEx, or STRB valid	0 wait state, C _L = 30 pF		9*		6*	ns
		1 wait state		t _{c(H)} + 9*		t _{c(H)} + 6*	ns

^{*} Not production tested

switching characteristics over recommended operating conditions for memory read/write[†] (see Figure 19, Figure 20, and Figure 21)

			VC33-120		VC33-150	
PARAMETER		MIN	MAX	MIN	MAX	UNIT
t _{d(H1L-SL)}	Delay time, H1 low to STRB low	-1*	4	-1*	3	ns
t _{d(H1L-SH)}	Delay time, H1 low to STRB high	-1*	4	-1*	3	ns
t _{d(H1H-RWL)W}	Delay time, H1 high to R/W low (write)	-1*	4	-1*	3	ns
t _{d(H1L-A)}	Delay time, H1 low to address valid	-1*	4	-1*	3	ns
t _{d(H1H-RWH)} W	Delay time, H1 high to R/W high (write)	-1*	4	-1*	3	ns
t _{d(H1H-A)W}	Delay time, H1 high to address valid on back-to-back write cycles (write)	-1*	4*	-1*	3*	ns
t _{v(H1L-D)W}	Valid time, Data after H1 low (write)		6		5	ns
t _{h(H1H-D)W}	Hold time, Data after H1 high (write)	0*	5	0*	5	ns

^{*} Not production tested

Output load characteristics for high-speed and low-speed (low-noise) output buffers are shown in Figure 19. High-speed buffers are used on A0 – A23, PAGEO – PAGE3, H1, H3, STRB, and R/W. All other outputs use the low-speed, (low-noise) output buffer.

[†] These timings assume a similar loading of 30 pF on all pins.

[‡] P = $t_{c(H)}/2$ (when duty cycle equals 50%).

[†] These timings assume a similar loading of 30 pF on all pins.

memory read/write timing (continued)

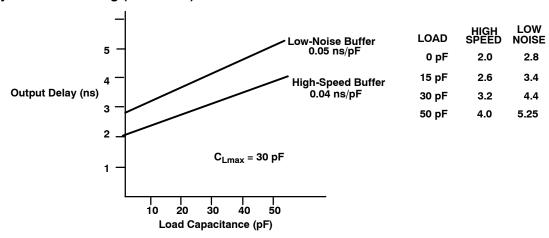


Figure 19. Output Load Characteristics, Buffer Only

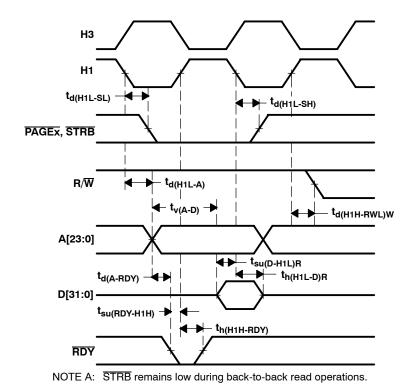


Figure 20. Timing for Memory ($\overline{STRB} = 0$ and $\overline{PAGEx} = 0$) Read

memory read/write timing (continued)

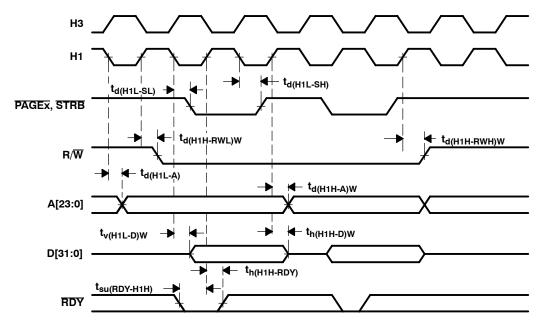


Figure 21. Timing for Memory ($\overline{STRB} = 0$ and $\overline{PAGEx} = 0$) Write

XF0 and XF1 timing when executing LDFI or LDII

The following tables define the timing parameters for XF0 and XF1 during execution of LDFI or LDII.

timing requirements for XF0 and XF1 when executing LDFI or LDII (see Figure 22)

		VC33-120	VC33-150	LINUT
		MIN MAX	MIN MAX	UNIT
t _{su(XF1-H1L)}	Setup time, XF1 before H1 low	5*	4*	ns
t _{h(H1L-XF1)}	Hold time, XF1 after H1 low	0*	0*	ns

^{*} Not production tested

switching characteristics over recommended operating conditions for XF0 and XF1 when executing LDFI or LDII (see Figure 22)

			3-120	VC33	3-150	
PARAMETER		MIN	MAX	MIN	MAX	UNIT
t _{d(H3H-XF0L)}	Delay time, H3 high to XF0 low		4		3	ns

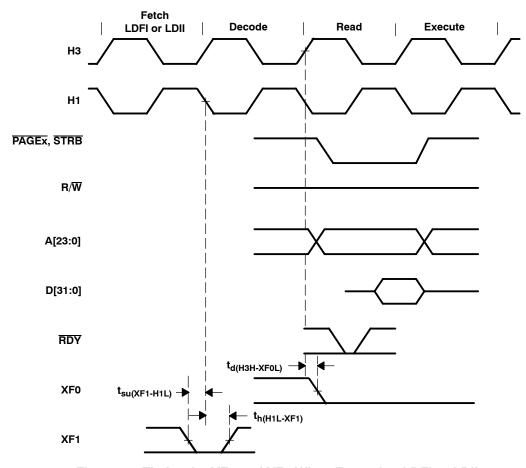


Figure 22. Timing for XF0 and XF1 When Executing LDFI or LDII

XF0 timing when executing STFI and STII[†]

The following table defines the timing parameters for the XF0 pin during execution of STFI or STII.

switching characteristics over recommended operating conditions for XF0 when executing STFI or STII (see Figure 23)

	VC33-120 VC33-150				
PARAMETER		MAX	MIN	MAX	UNIT
t _{d(H3H-XF0H)} Delay time, H3 high to XF0 high [†]		4		3	ns

[†] XF0 is always set high at the beginning of the execute phase of the interlock-store instruction. When no pipeline conflicts occur, the address of the store is also driven at the beginning of the execute phase of the interlock-store instruction. However, if a pipeline conflict prevents the store from executing, the address of the store is not driven until the store can execute.

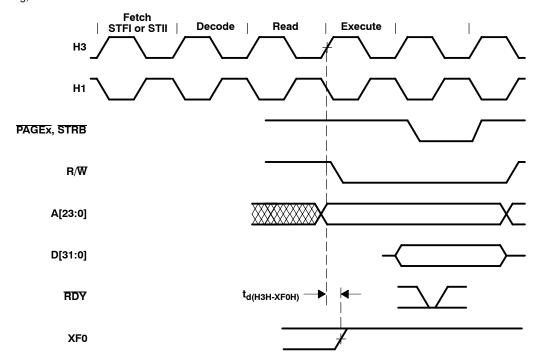


Figure 23. Timing for XF0 When Executing an STFI or STII

XF0 and XF1 timing when executing SIGI

The following tables define the timing parameters for the XF0 and XF1 pins during execution of SIGI.

timing requirements for XF0 and XF1 when executing SIGI (see Figure 24)

		VC33-120	VC33-150	LINUT
		MIN MAX	MIN MAX	UNIT
t _{su(XF1-H1L)}	Setup time, XF1 before H1 low	5*	4*	ns
t _{h(H1L-XF1)}	Hold time, XF1 after H1 low	0*	0*	ns

^{*} Not production tested

switching characteristics over recommended operating conditions for XF0 and XF1 when executing SIGI (see Figure 24)

	PARAMETER		3-120	VC33	LINIT	
			MAX	MIN	MAX	UNIT
t _{d(H3H-XF0L)}	Delay time, H3 high to XF0 low		4		3	ns
t _{d(H3H-XF0H)}	Delay time, H3 high to XF0 high		4		3	ns

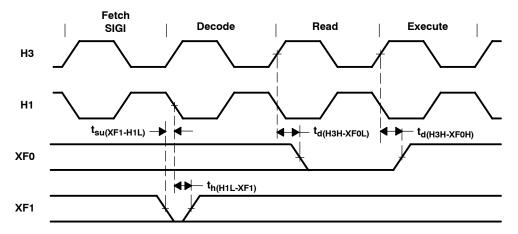


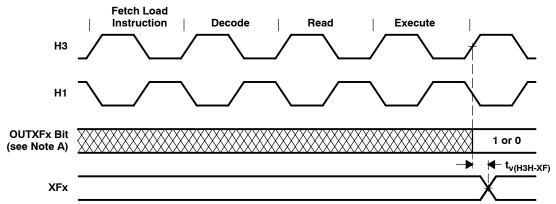
Figure 24. Timing for XF0 and XF1 When Executing SIGI

loading when XF is configured as an output

The following table defines the timing parameter for loading the XF register when the XFx pin is configured as an output.

switching characteristics over recommended operating conditions for loading the XF register when configured as an output pin (see Figure 25)

	PARAMETER	VC33	3-120	VC33	LINUT	
	PARAMETER		MAX	MIN	MAX	UNIT
t _{v(H3H-XF)}	Valid time, XFx after H3 high		4		3	ns



NOTE A: OUTXFx represents either bit 2 or 6 of the IOF register.

Figure 25. Timing for Loading XF Register When Configured as an Output Pin

changing XFx from an output to an input

The following table defines the timing parameters for changing the XFx pin from an output pin to an input pin.

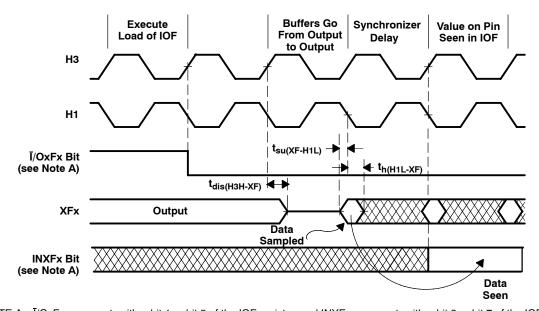
timing requirements for changing XFx from output to input mode (see Figure 26)

		VC33-120		VC33	LINUT	
			MAX	MIN	MAX	UNIT
t _{su(XF-H1L)}	Setup time, XFx before H1 low	5		4		ns
t _{h(H1L-XF)}	Hold time, XFx after H1 low	0		0		ns

switching characteristics over recommended operating conditions for changing XFx from output to input mode (see Figure 26)

	DADAMETED		VC33-120 VC33-150			LINUT
PARAMETER		MIN	MAX	MIN	MAX	UNIT
t _{dis(H3H-XF)}	Disable time, XFx after H3 high		6*		5*	ns

^{*} Not production tested



NOTE A: Ī/OxFx represents either bit 1 or bit 5 of the IOF register, and INXFx represents either bit 3 or bit 7 of the IOF register.

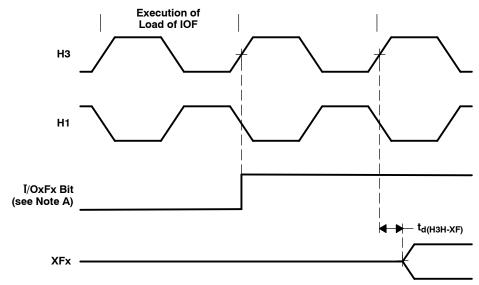
Figure 26. Timing for Changing XFx From Output to Input Mode

changing XFx from an input to an output

The following table defines the timing parameter for changing the XFx pin from an input pin to an output pin.

switching characteristics over recommended operating conditions for changing XFx from input to output mode (see Figure 27)

	VC33	3-120	VC33		
PARAMETER		MAX	MIN	MAX	UNIT
t _{d(H3H-XF)} Delay time, H3 high to XFx switching from input to output		4		3	ns



NOTE A: Ī/OxFx represents either bit 1 or bit 5 of the IOF register.

Figure 27. Timing for Changing XFx From Input to Output Mode

reset timing

RESET is an asynchronous input that can be asserted at any time during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 28 occurs; otherwise, an additional delay of one clock cycle is possible.

The asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.

Resetting the device initializes the bus control register to seven software wait states and therefore results in slow external accesses until these registers are initialized.

HOLD is a synchronous input that can be asserted during reset. It can take nine CPU cycles before HOLDA is granted.

The following table defines the timing parameters for the RESET signal. The numbers shown in Figure 28 correspond with those in the NO. column of the following table.

timing requirements for RESET (see Figure 28)

		VC3	3-120	VC33		
		MIN	MAX	MIN	MAX	UNIT
t _{su(RESET-EXTCLKL)}	Setup time, RESET before EXTCLK low	6*	P-7* [†]	5*	P - 7*†	ns
t _{su(RESETH-H1L)}	Setup time, $\overline{\text{RESET}}$ high before H1 low and after ten H1 clock cycles	6		5		ns

^{*} Not production tested

switching characteristics over recommended operating conditions for RESET (see Figure 28)

	DADAMETER	VC33	3-120	VC33-150		
	PARAMETER	MIN	MAX	MIN	MAX	UNIT
t _d (EXTCLKH-H1H)	Delay time, EXTCLK high to H1 high	2*	7*	2*	7*	ns
t _d (EXTCLKH-H1L)	Delay time, EXTCLK high to H1 low	2*	7*	2*	7*	ns
t _d (EXTCLKH-H3L)	Delay time, EXTCLK high to H3 low	2*	7*	2*	7*	ns
t _{d(EXTCLKH-H3H)}	Delay time, EXTCLK high to H3 high	2*	7*	2*	7*	ns
t _{dis(H1H-DZ)}	Disable time, Data (high impedance) from H1 high [‡]		7*		6*	ns
t _{dis(H3H-AZ)}	Disable time, Address (high impedance) from H3 high		7*		6*	ns
t _{d(H3H-CONTROLH)}	Delay time, H3 high to control signals high		4*		3*	ns
t _{d(H1H-RWH)}	Delay time, H1 high to R/\overline{W} high		4*		3*	ns
t _{d(H1H-IACKH)}	Delay time, H1 high to IACK high		4*		3*	ns
t _{dis(RESETL-ASYNCH)}	Disable time, Asynchronous reset signals disabled (high impedance) from $\overline{\text{RESET}}$ low§		7*		6*	ns

^{*} Not production tested

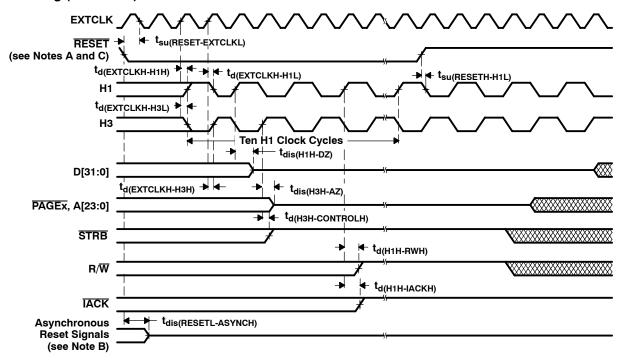


[†] P = t_{c(EXTCLK)}

[‡] High impedance for Dbus is limited to nominal bus keeper $Z_{OUT} = 15 \text{ k}\Omega$.

[§] Asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.

reset timing (continued)



- NOTES: A. Clock circuit is configured in C31-compatible divide-by-2 mode. If configured for x1 mode, EXTCLK directly drives H3.
 - B. Asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.
 - C. RESET is a synchronous input that can be asserted at any point during a clock cycle. If the specified timings are met, the exact sequence shown occurs; otherwise, an additional delay of one clock cycle is possible.
 - D. In microprocessor mode, the reset vector is fetched twice, with seven software wait states each time. In microcomputer mode, the reset vector is fetched twice, with no software wait states.
 - E. The address and PAGE3-PAGE0 outputs are placed in a high-impedance state during reset requiring a nominal 10-22 kΩ pullup. If not, undesirable spurious reads can occur when these outputs are not driven.

Figure 28. RESET Timing



interrupt response timing

The following table defines the timing parameters for the \overline{INTx} signals.

timing requirements for INT3-INT0 response (see Figure 29)

		VC33-120				VC33-15	0	LINUT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
t _{su(INT-H1L)}	Setup time, INT3- INT0 before H1 low	5*			4*			ns
t _{h(H1L-INT)}	Hold time, INT3- INT0 after H1 low			0			0	ns
t _{w(INT)}	Pulse duration, interrupt to ensure only one interrupt	P + 5* [†]	1.5P	2P - 5* [†]	P + 5*†	1.5P	2P - 5*†	ns

^{*} Not production tested

The interrupt (INTx) pins are synchronized inputs that can be asserted at any time during a clock cycle. The SM320C3x interrupts are selectable as level- or edge-sensitive. Interrupts are detected on the falling edge of H1. Therefore, interrupts must be set up and held to the falling edge of the internal H1 for proper detection. The CPU and DMA respond to detected interrupts on instruction-fetch boundaries only.

For the processor to recognize only one interrupt when level mode is selected, an interrupt pulse must be set up and held such that a logic-low condition occurs for:

- A minimum of one H1 falling edge
- No more than two H1 falling edges
- Interrupt sources whose edges cannot be specified to meet the H1 falling edge setup and hold times must be further restricted in pulse width as defined by t_{w(INT)} (parameter 51) in the table above.

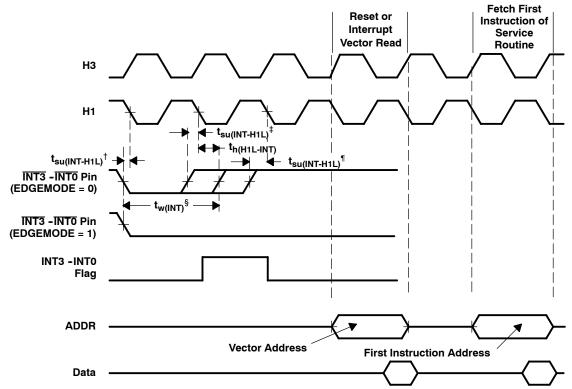
When EDGEMODE=1, the falling edge of the INTO-INT3 pins are detected using synchronous logic (see Figure 7). The pulse low and high time should be two CPU clocks or greater.

The SM320C3x can set the interrupt flag from the same source as quickly as two H1 clock cycles after it has been cleared.

If the specified timings are met, the sequence shown in Figure 29 occurs; otherwise, an additional delay of one clock cycle is possible.

 $^{^{\}dagger}$ P = $t_{c(H)}$

interrupt response timing (continued)



[†] Falling edge of H1 just detects $\overline{\text{INTx}}$ falling edge.

Figure 29. INT3-INTO Response Timing

[‡] Falling edge of H1 detects second INTx low, however flag clear takes precedence.

[§] Nominal width.

 $[\]P$ Falling edge of H1 misses previous $\overline{\text{INTx}}$ low as $\overline{\text{INTx}}$ rises.

interrupt-acknowledge timing

The IACK output goes active on the first half-cycle (HI rising) of the decode phase of the IACK instruction and goes inactive at the first half-cycle (HI rising) of the read phase of the IACK instruction.

The following table defines the timing parameters for the IACK signal. The numbers shown in Figure 30 correspond with those in the NO. column of the table below.

NOTE: The IACK instruction can be executed at anytime to signal an event. It is most often used within an interrupt routine to signal which interrupt has occurred.

switching characteristics over recommended operating conditions for IACK (see Figure 30)

	DADAMETED	VC33	3-120	VC33	3-150	
	PARAMETER	MIN	MAX	MIN	MAX	UNIT
t _{d(H1H-IACKL)}	Delay time, H1 high to IACK low	-1*	4	-1*	3	ns
t _{d(H1H-IACKH)}	Delay time, H1 high to IACK high	-1*	4	-1*	3	ns

^{*} Not production tested

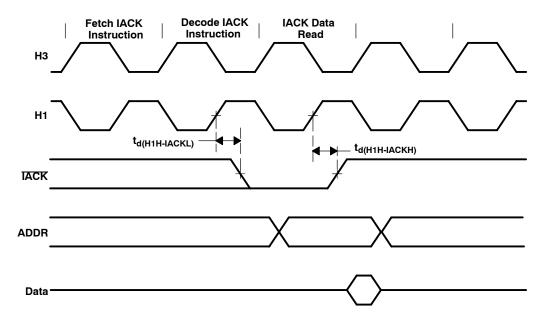


Figure 30. Interrupt Acknowledge (IACK) Timing

serial-port timing parameters

The following tables define the timing parameters for the serial port.

timing requirements (see Figure 31 and Figure 32)

		_	MIN	MAX	UNIT
	O dallina OHOVP	CLKX/R ext	t _{c(H)} x 2.6*		
t _{c(SCK)}	Cycle time, CLKX/R	CLKX/R int	t _{c(H)} x 4* [†]	t _{c(H)} x 2 ¹⁶ *	ns
	D. Land and the OHOV/D binds/land	CLKX/R ext	t _{c(H)} + 5		
t _{w(SCK)}	Pulse duration, CLKX/R high/low	CLKX/R int	[t _{c(SCK)} /2] - 4*	$[t_{c(SCK)}/2] + 4*$	ns
t _{r(SCK)}	Rise time, CLKX/R			3*	ns
t _{f(SCK)}	Fall time, CLKX/R			3*	ns
	0.1.17.014701	CLKR ext	4*		
t _{su(DR-CLKRL)}	Setup time, DR before CLKR low	CLKR int	5*		ns
		CLKR ext	3*		
t _h (CLKRL-DR)	Hold time, DR after CLKR low	CLKR int	0*		ns
	0.1.17. 500.17. 0140.1	CLKR ext	4*		
t _{su(FSR-CLKRL)}	Setup time, FSR before CLKR low	CLKR int	5*		ns
		CLKX/R ext	3*		
t _{h(SCKL-FS)}	Hold time, FSX/R input after CLKX/R low	CLKX/R int	0*		ns
	Catua time automal FCV hafeva CLIVV	CLKX ext	-[t _{c(H)} - 6]	[t _{c(SCK)} /2] - 6*	
su(FSX-CLKX)	Setup time, external FSX before CLKX	CLKX int	-[t _{c(H)} - 10]*	t _{c(SCK)} /2*	ns

^{*} Not production tested

switching characteristics over recommended operating conditions (see Figure 31 and Figure 32)

	PARAMETER		MIN	MAX	UNIT
t _{d(H1H-SCK)}	Delay time, H1 high to internal CLKX/R			4*	ns
	Dala Para OHOVIA DV alid	CLKX ext		6	
t _d (CLKX-DX)	Delay time, CLKX to DX valid	CLKX int		5*	ns
		CLKX ext		5	
t _d (CLKX-FSX)	Delay time, CLKX to internal FSX high/low	CLKX int		4*	ns
	Delay time, CLKX to first DX bit, FSX precedes CLKX	CLKX ext		4	
t _d (CLKX-DX)V	high	CLKX int		5*	ns
t _{d(FSX-DX)V}	X-DX)V Delay time, FSX to first DX bit, CLKX precedes FSX			6	ns
t _{dis(CLKX-DXZ)}	Disable time, DX high impedance following last data bit from CLKX high			6	ns

^{*} Not production tested

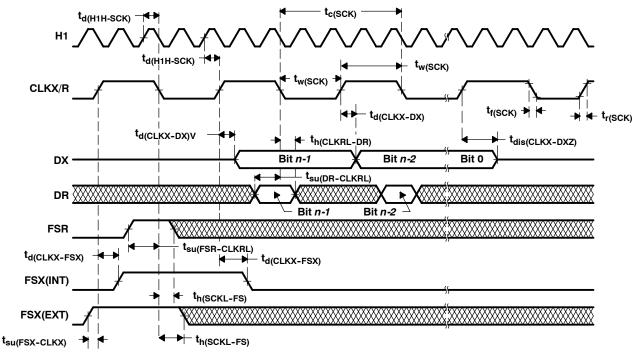


[†] A cycle time of t_{c(H)}*2 is possible when the device is operated at lower CPU frequencies. See the *TMS320VC33 Silicon Update* (literature number SPRZ176) for further details.

data-rate timing modes

Unless otherwise indicated, the data-rate timings shown in Figure 31 and Figure 32 are valid for all serial-port modes, including handshake. For a functional description of serial-port operation, see the *TMS320C3x User's Guide* (literature number SPRU031).

The serial-port timing parameters are defined in the preceding "serial-port timing parameters" tables. The numbers shown in Figure 31 and Figure 32 correspond with those in the NO. column of each table.



- NOTES: A. Timing diagrams show operations with CLKXP = CLKRP = FSXP = FSRP = 0.
 - B. Timing diagrams depend on the length of the serial-port word, where n = 8, 16, 24, or 32 bits, respectively.

CLKX/R t_{d(CLKX-FSX)} FSX(INT) t_{d(FSX-DX)}v t_{su(FSX-CLKX)} FSX(EXT) t_d(CLKX-DX) tdis(CLKX-DXZ) t_d(CLKX-DX)V DX Bit *n-1* Bit *n-2* Bit *n-3* Bit 0 th(SCKL-FS) **FSR** t_{su(FSR-CLKRL)} Bit *n-1* Bit *n-2* Bit *n-3* DR t_{su(DR-CLKRL)} th(CLKRL-DR)

Figure 31. Fixed Data-Rate Mode Timing

- NOTES: A. Timing diagrams show operation with CLKXP = CLKRP = FSXP = FSRP = 0.
 - B. Timing diagrams depend on the length of the serial-port word, where n = 8, 16, 24, or 32 bits, respectively.
 - C. The timings that are not specified expressly for the variable data-rate mode are the same as those that are specified for the fixed data-rate mode.

Figure 32. Variable Data-Rate Mode Timing



HOLD timing

HOLD is a synchronous input that can be asserted at any time during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 33 and Figure 34 occurs; otherwise, an additional delay of one clock cycle is possible.

The table, "timing parameters for HOLD/HOLDA", defines the timing parameters for the HOLD and HOLDA signals. The numbers shown in Figure 33 and Figure 34 correspond with those in the NO. column of the table.

The NOHOLD bit of the primary-bus control register overrides the HOLD signal. When this bit is set, the device comes out of hold and prevents future hold cycles.

Asserting HOLD prevents the processor from accessing the primary bus. Program execution continues until a read from or a write to the primary bus is requested. In certain circumstances, the first write is pending, thus allowing the processor to continue (internally) until a second external write is encountered.

Figure 33, Figure 34, and the accompanying timings are for a zero wait-state bus configuration. Since $\overline{\text{HOLD}}$ is internally captured by the CPU on the H1 falling edge one cycle before the present cycle is terminated, the minimum $\overline{\text{HOLD}}$ width for any bus configuration is, therefore, WTCNT+3. Also, $\overline{\text{HOLD}}$ should not be deasserted before $\overline{\text{HOLDA}}$ has been active for at least one cycle.

timing requirements for HOLD/HOLDA (see Figure 33 and Figure 34)

		VC33-1	20	VC33-1	50	
		MIN	MAX	MIN	MAX	UNIT
t _{su(HOLD-H1L)}	Setup time, HOLD before H1 low	4		3		ns
$t_{w(HOLD)}$	Pulse duration, HOLD low	3t _{c(H)} *		3t _{c(H)} *		ns

^{*}Not production tested.

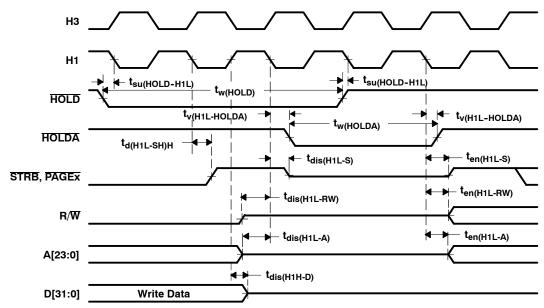
switching characteristics over recommended operating conditions for HOLD/HOLDA (see Figure 33 and Figure 34)

	DADAMETED	VC33-1	20	VC33-1	50	
PARAMETER		MIN	MAX	MIN	MAX	UNIT
t _{v(H1L-HOLDA)}	Valid time, HOLDA after H1 low	-1*	4*	-1*	3*	ns
t _{w(HOLDA)}	Pulse duration, HOLDA low	2t _{c(H)} - 4*		2t _{c(H)} - 4*		ns
t _{d(H1L-SH)H}	Delay time, H1 low to STRB high for a HOLD	-1	4	-1	3	ns
t _{dis(H1L-S)}	Disable time, STRB to the high-impedance state from H1 low		5		4	ns
t _{en(H1L-S)}	Enable time, STRB enabled (active) from H1 low		5		4	ns
t _{dis(H1L-RW)}	Disable time, R/W to the high-impedance state from H1 low		5*		5*	ns
t _{en(H1L-RW)}	Enable time, R/W enabled (active) from H1 low		5		4	ns
t _{dis(H1L-A)}	Disable time, Address to the high-impedance state from H1 low		5*		4*	ns
t _{en(H1L-A)}	Enable time, Address enabled (valid) from H1 low		5		5	ns
t _{dis(H1H-D)}	Disable time, Data to the high-impedance state from H1 high		5*		4*	ns

^{*} Not production tested



HOLD timing (continued)



NOTE A: HOLDA goes low in response to HOLD going low and continues to remain low until one H1 cycle after HOLD goes back high.

Figure 33. Timing for HOLD/HOLDA (After Write)

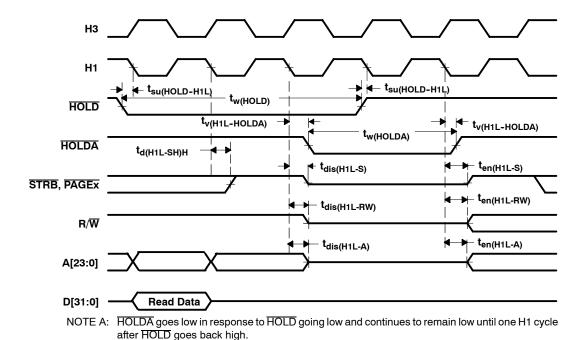


Figure 34. Timing for HOLD/HOLDA (After Read)

general-purpose I/O timing

Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The contents of the internal control registers associated with each peripheral define the modes for these pins.

peripheral pin I/O timing

The following table shows the timing parameters for changing the peripheral pin from a general-purpose output pin to a general-purpose input pin and vice versa.

timing requirements for peripheral pin general-purpose I/O (see Note 1, Figure 35, and Figure 36)

		VC33	3-120	VC33	-150	
		MIN	MAX	MIN	MAX	UNIT
t _{su(GPIO-H1L)}	Setup time, general-purpose input before H1 low	4*		3*		ns
t _{h(H1L-GPIO)}	Hold time, general-purpose input after H1 low	0*		0*		ns

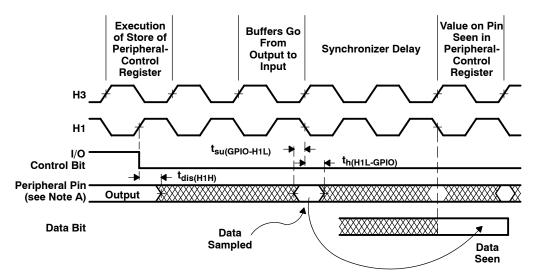
^{*} Not production tested

NOTE 1: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.

switching characteristics over recommended operating conditions for peripheral pin general-purpose I/O (see Note 1, Figure 35, and Figure 36)

	PARAMETER				-150	LINUT
					MAX	UNIT
t _{d(H1H-GPIO)}	Delay time, H1 high to general-purpose output		5		4	ns
t _{dis(H1H)}	Disable time, general-purpose output from H1 high		7		5	ns

NOTE 1: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.

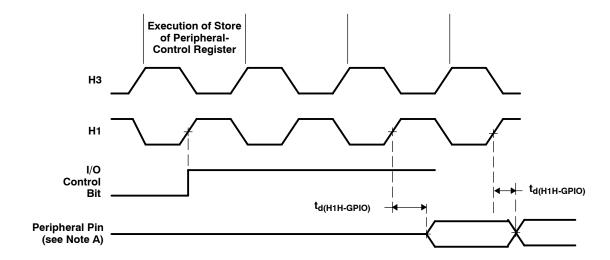


NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

Figure 35. Change of Peripheral Pin From General-Purpose Output to Input Mode Timing



peripheral pin I/O timing (continued)



NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

Figure 36. Change of Peripheral Pin From General-Purpose Input to Output Mode Timing

timer pin timing

Valid logic-level periods and polarity are specified by the contents of the internal control registers. The following tables define the timing parameters for the timer pin.

timing requirements for timer pin (see Figure 37 and Figure 38)

		VC	33-120	VC	33-150	UNIT
		MIN	MAX	MIN	MAX	UNIT
t _{su(TCLK-H1L)} †	Setup time, TCLK external before H1 low	4*		3*		ns
t _{h(H1L-TCLK)} †	Hold time, TCLK external after H1 low	0		0		ns

^{*} Not production tested

switching characteristics over recommended operating conditions for timer pin (see Figure 37 and Figure 38)

PARAMETER			VC3	3-120	VC3	3-150	
			MIN	MAX	MIN	MAX	UNIT
t _{d(H1H-TCLK)}	Delay time, H1 high internal valid	to TCLK		4		3	ns
. +	O dell'es TOLK	TCLK ext	t _{c(H)} x 2.6*		t _{c(H)} x 2.6*		
t _{c(TCLK)} ‡	Cycle time, TCLK	TCLK int	t _{c(H)} x 2*	t _{c(H)} x 2 ^{32*}	t _{c(H)} x 2*	t _{c(H)} x 2 ³² *	ns
+±	Pulse duration,	TCLK ext	t _{c(H)} + 6*		t _{c(H)} + 5*		20
t _{w(TCLK)} ∓	TCLK	TCLK int	[t _{c(TCLK)} /2] - 4*	[t _{c(TCLK)} /2] + 4*	[t _{c(TCLK)} /2] - 4*	[t _{c(TCLK)} /2] + 4*	ns

^{*} Not production tested

[‡] These parameters are applicable for an asynchronous input clock.

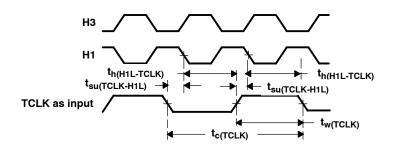


Figure 37. Timer Pin Timing, Input

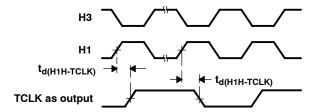


Figure 38. Timer Pin Timing, Output



[†] These requirements are applicable for a synchronous input clock.

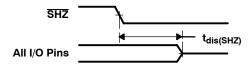
SHZ pin timing

The following table defines the timing parameter for the SHZ pin.

switching characteristics over recommended operating conditions for SHZ (see Figure 39)

PARAMETER	MIN	MAX	UNIT
$t_{dis(SHZ)} \qquad \text{Disable time, } \overline{SHZ} \text{ low to all outputs, I/O pins disabled (high impedance)}$	0*	8*	ns

^{*} Not production tested



NOTE A: Enabling SHZ destroys SM320VC33-EP register and memory contents. Assert SHZ = 1 and reset the SM320VC33-EP to restore it to a known condition.

Figure 39. Timing for SHZ

Test access port timing

The following table defines the timing parameter for the test access port.

timing for test access port (see Figure 40)

		VC33	VC33-120		VC33-150	
		MIN	MAX	MIN	MAX	UNIT
t _{su(TMS-TCKH)}	Setup time, TMS/TDI to TCK high	5*		5*		ns
t _{h(TCKH-TMS)}	Hold time, TMS/TDI from TCK high	5*		5*		ns
t _{d(TCKL-TDOV)}	Delay time, TCK low to TDO valid	0*	10*	0*	10*	ns
t _{r (TCK)}	Rise time, TCK		3*		3*	ns
t _{f (TCK)}	Fall time, TCK		3*		3*	ns

^{*} Not production tested

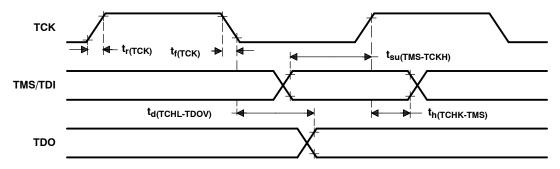
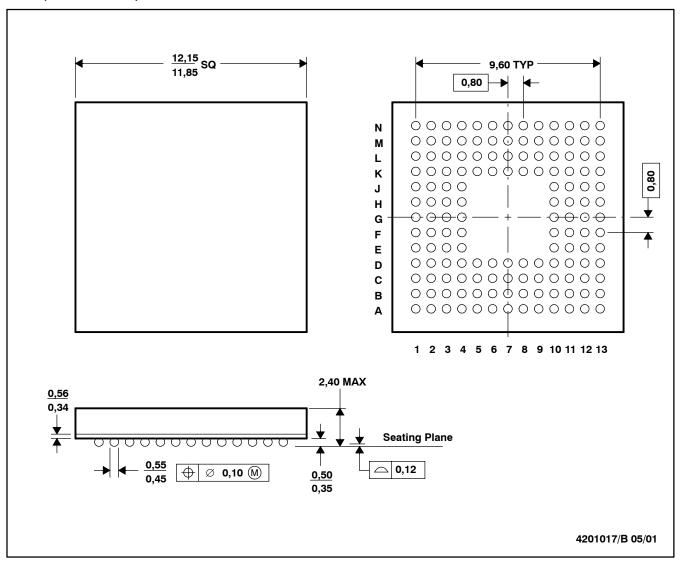


Figure 40. Test Access Port Timings

MECHANICAL DATA

GNM (S-CBGA-N144)

CERAMIC BALL GRID ARRAY



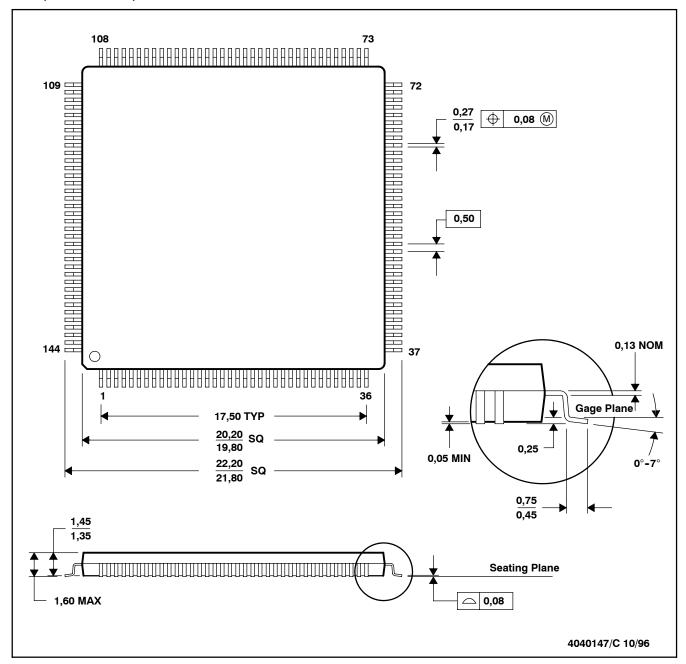
NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

MECHANICAL DATA

PGE (S-PQFP-G144)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-026

Thermal Resistance Characteristics

PARAMETER	°C/W
R_{\ThetaJA}	56
$R_{\Theta JC}$	5



9-May-2012

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
SM320VC33GNMM150EP	ACTIVE	CBGA	GNM	144	160	TBD	Call TI	Level-1-235C-UNLIM	Add to cart
SM320VC33PGEA120EP	ACTIVE	LQFP	PGE	144	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	Add to cart
V62/03610-01XE	ACTIVE	LQFP	PGE	144	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	Add to cart
V62/03610-02YA	ACTIVE	CBGA	GNM	144	160	TBD	Call TI	Level-1-235C-UNLIM	Add to cart

(1) The marketing status values are defined as follows:

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NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

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Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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Catalog: SM320VC33





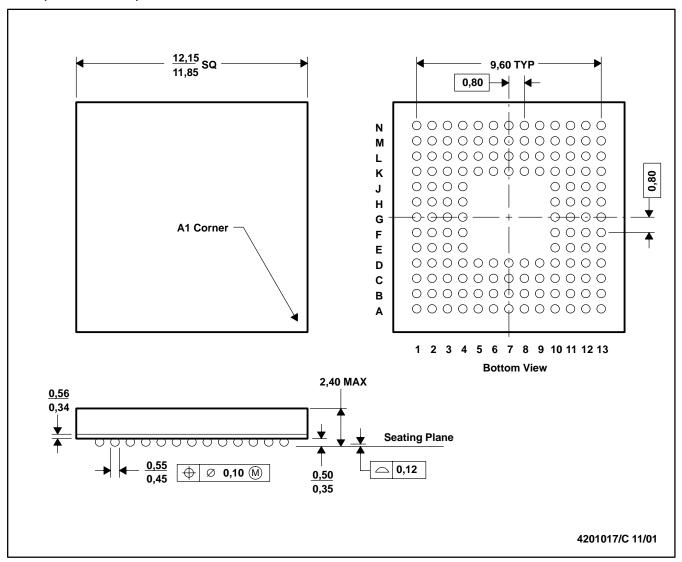
9-May-2012

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

GNM (S-CBGA-N144)

CERAMIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

PGE (S-PQFP-G144)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

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